## Angle Sensor

GMR-Based Angle Sensor
TLE5012B

## User's Manual

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User's Manual

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## 1 Product Description




Figure 1-1 PG-DSO-8 package

### 1.1 Overview

The TLE5012B is a $360^{\circ}$ angle sensor that detects the orientation of a magnetic field. This is achieved by measuring sine and cosine angle components with monolithically integrated Giant Magneto Resistance (iGMR) elements. These raw signals (sine and cosine) are digitally processed internally to calculate the angle orientation of the magnetic field (magnet).

The TLE5012B is a pre-calibrated sensor. The calibration parameters are stored in laser fuses. At start-up the values of the fuses are written into flip-flops, where these values can be changed to application-specific parameters. The precision of the angle measurement, over a wide temperature range and a long lifetime, can be improved by enabling an optional internal autocalibration algorithm.

Data communications are accomplished with a bi-directional Synchronous Serial Communication (SSC) that is SPI-compatible. The sensor configuration is stored in registers, which are accessible by the SSC interface.
Additionally four other interfaces are available with the TLE5012B: Pulse-Width-Modulation (PWM) Protocol, Short-PWM-Code (SPC) Protocol, Hall Switch Mode (HSM) and Incremental Interface (IIF). These interfaces can be used in parallel with SSC or alone. Pre-configured sensor derivates with different interface settings are also available. See the derivate ordering codes in the TLE5012B Data Sheet. A description of the derivates can also be seen in Chapter 7.

Online diagnostic functions are provided to ensure reliable operation.

## $1.2 \quad$ Features

- Giant Magneto Resistance (GMR)-based principle
- Integrated magnetic field sensing for angle measurement
- $360^{\circ}$ angle measurement with revolution counter and angle speed measurement
- Two separate highly accurate single bit SD-ADC
- 15 bit representation of absolute angle value on the output (resolution of $0.01^{\circ}$ )
- 16 bit representation of sine / cosine values on the interface
- Max. $1.0^{\circ}$ angle error over lifetime and temperature-range with activated auto-calibration
- Bi-directional SSC Interface typ. 8Mbit/s
- Supports Safety Integrity Level (SIL) with diagnostic functions and status information
- Interfaces: SSC, PWM, Incremental Interface (IIF), Hall Switch Mode (HSM), Short PWM Code (SPC, based on SENT protocol defined in SAE J2716)
- Output pins can be configured (programmed or pre-configured) as push-pull or open-drain
- Bus mode operation of multiple sensors on one line is possible with SSC or SPC interface in open-drain configuration
- $0.25 \mu \mathrm{~m}$ CMOS technology
- Automotive qualified: $-40^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ (junction temperature)
- ESD > 4kV (HBM)
- RoHS compliant (Pb-free package)
- Halogen-free


### 1.3 Application Example

The TLE5012B GMR-based angle sensor is designed for angular position sensing in automotive applications such as:

- Electrically commutated motor (e.g. Electric Power Steering (EPS), Brushless DC electric motors (BLDC))
- Rotary switches
- Steering angle measurements
- General angular sensing

The TLE5012B is also used in various non-automotive applications.


Figure 1-2 A usual application for TLE5012B is the electrically commutated motor

## 2 Functional Description

### 2.1 Block Diagram



Figure 2-1 TLE5012B block diagram

### 2.2 Functional Block Description

### 2.2.1 Internal Power Supply

The internal stages of the TLE5012B are supplied with several voltage regulators:

- GMR Voltage Regulator, VRG
- Analog Voltage Regulator, VRA
- Digital Voltage Regulator, VRD (derived from VRA)

These regulators are directly connected to the supply voltage $\mathrm{V}_{\mathrm{DD}}$.

### 2.2.2 Oscillator and PLL

The digital clock of the TLE5012B is provided by the Phase-Locked Loop (PLL), which is by default fed by an internal oscillator. In order to synchronize the TLE5012B with other ICs in a system, the TLE5012B can be
configured via SSC interface to use an external clock signal supplied on the IFC pin as the PLL source, instead of the internal clock. External clock mode is only available in the PWM or SPC interface configurations.

### 2.2.3 SD-ADC

The Sigma-Delta Analog-Digital-Converters (SD-ADC) transform the analog GMR voltages and temperature voltage into the digital domain.

### 2.2.4 Digital Signal Processing Unit

The Digital Signal Processing Unit (DSPU) contains the:

- Intelligent State Machine (ISM), which does error compensation of offset, offset temperature drift, amplitude synchronicity and orthogonality of the raw signals from the GMR bridges, and performs additional features such as auto-calibration, prediction and angle speed calculation
- COordinate Rotation Dlgital Computer (CORDIC), which contains the trigonometric function for angle calculation
- Capture Compare Unit (CCU), which is used to generate the PWM and SPC signals
- Random Access Memory (RAM), which contains the configuration registers
- Laser Fuses, which contain the calibration parameters for the error-compensation and the IC default configuration, which is loaded into the RAM at startup


## Laser fuses configuration

The laser fuse settings are derivate specific. During production, each and every TLE5012B chip is specifically configured according to a derivate interface (PWM, SPC, HSM or IIF) and to its specific calibration values (e.g. offset, amplitude synchronicity, orthogonality). These default values are set by laser fuses, where they remain stored permanently. At power-on the values stored in the fuses are loaded into flip-flops (placed in the RAM).
Via the SSC interface, these derivate specific configuration values can be overwritten in the RAM. This allows some programmability such as change of interface (using a IIF derivate as a PWM derivate for example) or to correct the calibration values (if running the autocalibration mode for example). It is highly recommended to configure the sensor with customized settings right after a Hardware reset (within the first $120 \mu \mathrm{~s}$, prior to start of the Built-In Self-Test). If this interval is not sufficient, it is also possible to configure the sensor after the power-on time. To ensure a correct configuration after power-on time, see recommendations on Chapter 6. When powered off or reset, the overwritten values will be lost and the default values stored in the fuses will be reloaded into the RAM at the next power up.
The Figure 2-2 shows how the fuse burning process works. In the original state all fuses are connected to ground (GND). Once the calibration and derivate specific values are calculated, the information is burned into the fuses, so that some remain connected to GND ("low" or logical "0") and some are now pulled up by a resistor ("high" or logical " 1 "). When powering the sensor, the RAM is initialized with the values from the fuses.


Figure 2-2 Laser Fuses burning process

### 2.2.5 Interfaces

Bi-directional communication with the TLE5012B is enabled by a three-wire SSC interface. In parallel to the SSC interface, one secondary interface can be selected, which is available on the IFA, IFB, IFC pins:

- PWM
- Incremental Interface
- Hall Switch Mode
- Short PWM Code

By using pre-configured derivates (see Chapter 7), the TLE5012B can also be operated with the secondary interface only, without SSC communication.

### 2.2.6 Safety Features

The TLE5012B offers a multiplicity of safety features to support the Safety Integrity Level (SIL). Infineon's sensors that are intended for this purpose are identified by the following logo:

## PRO

Figure 2-3 PRO-SIL ${ }^{\text {TM }}$ Logo

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The PRO-SIL ${ }^{\text {™ }}$ Trademark designates Infineon products which contain SIL Supporting Features.
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SIL respectively A-SIL certification for such a System has to be reached on system level by the System Responsible at an accredited Certification Authority.
SIL stands for Safety Integrity Level (according to IEC 61508)
A-SIL stands for Automotive-Safety Integrity Level (according to ISO 26262)

## Safety features are:

- Test vectors switchable to ADC input (activated via SSC interface)
- Inversion or combination of filter input streams (activated via SSC interface)
- Data transmission check via 8-bit Cyclic Redundancy Check (CRC) for SSC communcation and 4-bit CRC nibble for SPC interface
- Built-in Self-test (BIST) routines for ISM, CORDIC, CCU, ADCs performed at startup
- Two independent active interfaces possible
- Overvoltage and undervoltage detection


### 2.3 Sensing Principle

The Giant Magneto Resistance (GMR) sensor is implemented using vertical integration. This means that the GMR-sensitive areas are integrated above the logic part of the TLE5012B device. These GMR elements change their resistance depending on the direction of the magnetic field.
Four individual GMR elements are connected to one Wheatstone sensor bridge for each of the two components of the applied magnetic field:

- X component, $\mathrm{V}_{\mathrm{x}}$ (cosine) and the
- Y component, $\mathrm{V}_{\mathrm{y}}$ (sine)

With this full-bridge structure the maximum GMR signal is available and temperature effects cancel out each other.


Figure 2-4 Sensitive bridges of the GMR sensor (not to scale)

## Attention: Due to the rotational placement inaccuracy of the sensor IC in the package, the sensors $0^{\circ}$ position may deviate by up to $3^{\circ}$ from the package edge direction indicated in Figure 2-4.

In Figure 2-4, the arrows in the resistors represent the magnetic direction which is fixed in the Reference Layer. On top of the Reference Layer, and separated by a non magnetic layer, there is a Free Layer. When applying an external magnetic field the Free Layer moves in the same direction as the external magnetic field, while the Reference Layer remains fix. The resistance of the GMR elements depends on the magnetic direction difference between the Reference Layer and the Free Layer.
When the external magnetic field is parallel to the direction of the Reference Layer, the resistance is minimal (Reference Layer and Free Layer are parallel). When the external magnetic field and the Reference Layer are antiparallel (Reference Layer and Free Layer are anti-parallel), resistance is maximal.
The output signal of each bridge is only unambiguous over $180^{\circ}$ between two maxima. Therefore two bridges are oriented orthogonally to each other to measure $360^{\circ}$.

With the trigonometric function ARCTAN2, the true $360^{\circ}$ angle value is calculated out of the raw X and Y signals from the sensor bridges.

TLE5012B

Functional Description


Figure 2-5 Ideal output of the GMR sensor bridges
$\qquad$

### 2.4 Pin Configuration



Figure 2-6 Pin configuration (top view)

### 2.5 Pin Description

Table 2-1 Pin Description

| Pin No. | Symbol | In/Out | Function |
| :--- | :--- | :--- | :--- |
| 1 | IFC <br> (CLK / IIF_IDX / HS3) | I/O | Interface C: <br> External Clock 1 / / IIF Index / Hall Switch <br> Signal 3 |
| 2 | SCK | I | SSC Clock |
| 3 | CSQ | I | SSC Chip Select |
| 4 | DATA | I/O | SSC Data |
| 5 | IFA <br> (IIF_A / HS1 / PWM / SPC) | I/O | Interface A: <br> IIF Phase A / Hall Switch Signal 1 / <br> PWM / SPC output (input for SPC trigger <br> only) |
| 6 | V DD | - | Supply Voltage |
| 7 | GND | - | Ground |
| 8 | IFB <br> (IIF_B / HS2) | Interface B: <br> IIF Phase B / Hall Switch Signal 2 |  |

[^0]
## 3 Application Circuits

The application circuits in this chapter show the various communication possibilities of the TLE5012B. The pin output mode configuration is device-specific and it can be either push-pull or open-drain. The bit IFAB_OD (register IFAB, ODH) indicates the output mode for the IFA, IFB and IFC pins. The SSC pins are by default pushpull (bit SSC_OD, register MOD_3, 09H). Every application circuits below are using otherwise specified SSC with push-pull configuration and the internal clock.

### 3.1 IIF interface and SSC (IIF in push-pull configuration)

Figure 3-1 shows a block diagram of a TLE5012B with Incremental Interface (IIF) and SSC interface. The derivate TLE5012B - E1000 is by default configured with push-pull IFA (IIF_A), IFB (IIF_B) and IFC (IIF_IDX) pins. When the output pins are configurated as open-drain, three pull-up resistors should be added (e.g. $2 \mathrm{k} 2 \Omega$ ) between the data lines and VDD.


Figure 3-1 Application circuit for TLE5012B with IIF interface and SSC

### 3.2 HSM interface and SSC (HSM in push-pull configuration)

Figure 3-2 shows a block diagram of the TLE5012B with Hall Switch Mode (HSM) and SSC interface. The derivate TLE5012B - E3005 is by default configurated with push-pull IFA (HS1), IFB (HS2) and IFC (HS3) pins.


Rs2 recommended, e.g. $470 \Omega$
Figure 3-2 Application circuit for TLE5012B with HSM interface (push-pull configuration) and SSC

### 3.3 HSM interface and SSC (HSM in open-drain configuration)

As shown in Figure 3-3 when IFA, IFB and IFC are configurated via the SSC interface as open drain pins, three pull-up resistors (Rpu) should be added on the output lines.


Rs1 recommended, e.g. $100 \Omega$
Rs2 recommended, e.g. $470 \Omega$ Rpu required, e.g. $2 \mathrm{~K} 2 \Omega$
Figure 3-3 Application circuit for TLE5012B with HSM interface (open-drain configuration) and SSC

### 3.4 PWM interface (push-pull configuration)

The TLE5012B can be configured with PWM only (Figure 3-4). The derivate TLE5012B - E5000 is by default configurated with push-pull configuration for IFA (PWM) pin. Internal pull-up resistors are always available for DATA and CSQ pins (see Datasheet). It is recommended to connect CSQ pin to $V_{D D}$ to provide a high level and avoid unintentional activation of the SSC interface. DATA pin should be left open. The figure below shows a typical implementation of the TLE5012B - E5000.


Rpd recommended, e.g. $10 \mathrm{k} \Omega$
Figure 3-4 Application circuit for TLE5012B with PWM (push-pull configuration) interface

### 3.5 PWM interface (open-drain configuration)

The TLE5012B - E5020 is also a PWM derivate but with open drain for IFA (PWM) pin. A pull-up resistor (e.g. $2.2 \mathrm{k} \Omega$ ) should be added between the IFA line and VDD, as shown in Figure 3-5.
Internal pull-up resistors are always available for DATA and CSQ pins (see Datasheet). It is recommended to connect CSQ pin to $V_{D D}$ to provide a strong level and avoid unintentional activation of the SSC interface. DATA pin should be left open. The figure below shows a typical implementation of the TLE5012B - E5020.


Figure 3-5 Application circuit for TLE5012B with PWM (open-drain configuration) interface

### 3.6 SPC interface

The TLE5012B can be configured with SPC only (Figure 3-6). This is only possible with the TLE5012B - E9000 derivate, which is by default configurated with an open-drain IFA (SPC) pin.
In Figure 3-6 the IFC (S_NR[1]) and SCK (S_NR[0]) pins are set to ground to generate the slave number (S_NR) $0_{D}$ (or $00_{B}$ ). In case of SCK (S_NR[0]) needs to be set to VDD to generate another slave address, CSQ pin should be set to ground instead. Internal pull-up resistors are always available for DATA and CSQ pins (see Datasheet). DATA pin should be left open. Since SCK and CSQ pins should have opposite level, it is not recommended to use the SSC interface in parallel.


Figure 3-6 Application circuit for TLE5012B with SPC interface

### 3.7 SSC interface (push-pull configuration)

In Figure 3-1, Figure 3-2 and Figure 3-3 the SSC interface has the default push-pull configuration (see details in Figure 3-7). A series resistor on the DATA line is recommended to limit the current in erroneous cases (e.g. the sensor pushes high and the microcontroller pulls low at the same time or vice versa). Resistors on SCK and CSQ lines are recommended in case of disturbances or noise.


Figure 3-7 SSC interface with push-pull configuration (high-speed application)

### 3.8 SSC interface (open-drain configuration)

It is possible to use an open-drain configuration for the DATA line. This setup can be used to communicate with a microcontroller in a bus system, together with other SSC slaves (e.g. two TLE5012B devices for redundancy reasons). This mode can be activated using the bit SSC_OD.
Even though, push-pull configuration in a bus system is also possible since the addressing of the sensor is perfomed with CSQ pin.
The open-drain configuration can be seen in Figure 3-8. Series resistors on the DATA line are recommended to limit the current in erroneous cases. Resistors on SCK and CSQ lines are recommended in case of disturbances or noise A pull-up resistor of typ. $1 \mathrm{k} \Omega$ is required on the DATA line.


Figure 3-8 SSC interface with open-drain configuration (bus systems)

## Application Circuits

### 3.9 Sensor supply in bus mode

When using two or more devices in a bus configuration (SSC or SPC interface). It is recommended to use the same supply for every sensors connected to the bus. In case of a power loss the unpowered device is sinking current through the OUT pin. Depending on the external circuitry the additional current flow might disturb the bus behavior.

The figure below (Figure 3-9) shows a typical implementation of a bus mode using SPC interface. External components such as EMC filter or additional series resistors are not represented for clarity purpose. Only the pullup resistor Rpu is shown.


Figure 3-9 Sensors' supply in bus mode

## 4 Specification

### 4.1 Autocalibration

Autocalibration enables online parameter calculation, and therefore reduces angle error due to temperature and lifetime drifts.
The TLE5012B is a pre-calibrated sensor; at start-up the parameters stored in the laser fuses are loaded into flipflops. During operation, the TLE5012B needs 1.5 revolutions to generate new autocalibration parameters. The parameters are updated with new autocalibration parameters according to the mode selected via the AUTOCAL bits (Mode 2 register). The parameters are updated in a smooth way to avoid an angle jump on the output; only one Least-Significant Bit (LSB) will be changed within the chosen range or time. Once the parameters are updated, a new autocalibration parameter generation starts, as autocalibration is done continuously.

## AUTOCAL Modes:

- 00: No autocalibration
- 01: Autocalibration Mode 1. Parameters are updated by one LSB at every update time $\mathrm{t}_{\text {upd }}$ (dependent on FIR_MD setting) till the new autocalibration parameter values are reached.
- 10: Autocalibration Mode 2. Parameters are updated by one LSB only. After the update, autocalibration will already calculate new parameters again.
- 11: Autocalibration Mode 3. Parameters are updated by one LSB at every angle range of $11.25^{\circ}$ till the new autocalibration parameter values are reached.


Figure 4-1 Parameter correction with autocalibration mode 1


Figure 4-2 Parameter correction with autocalibration mode 2


Figure 4-3 Parameter correction with autocalibration mode 3
The autocalibration mode 1 is the quickest mode to correct the parameters. Mode 2 is the slowest method, but since the parameters are updated by one digit only, it offers robustness against corrupted maxima - minima pair (in case of a spike, for example).

## Condition for usability of Autocalibration:

The autocalibration algorithm relies on the collection of maximum and minimum values of the raw X - and Y -signals of the sensing elements, therefore it is suitable for applications where a rotor is continuously turning (full $360^{\circ}$ rotations). Compensation parameters for offset and amplitude synchronicity error are calculated from these minima and maxima only if the temperature did not change by more than 5 Kelvin during their collection, to avoid temperature-drift induced errors.
For the sensor to be accurate in autocalibration mode, it has to be assured in the application that the calibration parameters are updated frequently. Thus, autocalibration should only be used in applications where the magnet regularly rotates by at least one full turn (internal TLE5012B check of full turn requires maximum 1.5 revolutions) at a temperature which is constant within 5 Kelvin.

## Enabling/Disabling of Autocalibration:

When switching autocalibration on or off, the TLE5012B may erroneously trigger the S_FUSE error bit in the status register, which indicates a configuration CRC error, which is also displayed permanently in the Safety Word of the SSC communication.

When autocalibration is ON and has to be disabled: write the correct CRC for autocalibration OFF before disabling autocalibration. This way the sensor will see a consistent state when the first runtime CRC check is done again and no CRC error will occur. The correct CRC must be calculated on the microcontroller side.
When autocalibration is OFF and has to be enabled or just restarted: after switching the autocalibration mode ON, the Status Register should be read via SSC after three $t_{\text {update }}$ periods and an occurring S_FUSE error should be ignored

## Changing TLE5012B default Configuration, if Autocalibration is enabled

Changing certain TLE5012B default configurations while autocalibration is enabled could lead to corrupted autocalibration parameters. Therefore, disable autocalibration prior to change the angle direction (ANG_DIR bit on MOD_2 register), prediction (PREDICT bit on MOD_2 register) or the angle base (ANG_BASE bits on MOD_3 register). Once these parameters have been changed, enable autocalibration again.
An initialization sequence for the case of changing angle direction is shown in Table 4-1. This sequence is also valid for prediction and for angle base. In case of angle base additonal write after the first write is required in order to re-configure the new angle base value.

Table 4-1 Initialization via SSC / SPI to change ANG_DIR

| Step | Command type | Register | Value | Description |
| :--- | :--- | :--- | :--- | :--- |
| 0 (default) | - | MOD_2 | 0x0801 | Angle Range $=360^{\circ}$, Angle Direction = counter clockwise, <br> Autocal = on |
| 1 | W (write) | MOD_2 | $0 \times 0808$ | Angle Range $=360^{\circ}$, Angle Direction = clockwise, Autocal = <br> off |
| 2 | Wait | - | Autocal is being deactivated, and Angle direction can be <br> changed. The deactivated autocal stops any running <br> min/max search and clears the min/max_x/y registers before <br> any offset (and amplitude) parameters can change. |  |
|  |  |  |  |  |

### 4.1.1 Angle Error adder with Autocalibration enabled

With constant temperatures ( $\Delta T<5$ Kelvin) or parts rotating faster than the temperature changes, the autocalibration angle error is as specified in the TLE5012B Data Sheet. If autocalibration is enabled when the temperature changes by more than 5 Kelvin within 1.5 revolutions, the last valid autocalibration parameters will still be used, leading to an additional angle error. Such cases will happen when the rotating part is halted and the temperature is changing by more than 5 Kelvin or the rotating part is moving too slowly compared to the external temperature changes (see Figure 4-4).


Figure 4-4 Cases where an angle error adder has to be included if autocalibration is enabled

The angle error adder is described in the TLE5012B Data Sheet (Figure 4-3, page \#25 on the TLE5012B Data Sheet, Rev. 2.0 from 2014-02) and depends on the initial temperature. To read the right angle error adder select the initial temperature and move through the x-axis as many degrees as the delta between the final temperature and the initial temperature. Then read the y-axis value at this delta and add it to the specified angle error, which already contains lifetime drifts. Some cases are shown in Table 4-2:

Table 4-2 Additional angle error examples

| $\mathbf{T}_{\text {junction }}$ range | Autocal | T/1.5 revolutions | Additional angle error |
| :--- | :--- | :--- | :--- |
| $-40^{\circ} \mathrm{C} \ldots 150^{\circ} \mathrm{C}$ | Off | - | No additional angle error |
| $-40^{\circ} \mathrm{C} \ldots 150^{\circ} \mathrm{C}$ | On | $<5$ Kelvin | No additional angle error |
| $-40^{\circ} \mathrm{C} \ldots 150^{\circ} \mathrm{C}$ | On | 10 Kelvin | $<0.2^{\circ}$ |
| $-40^{\circ} \mathrm{C} \ldots 150^{\circ} \mathrm{C}$ | On | 20 Kelvin | $<0.35^{\circ}$ |
| $-40^{\circ} \mathrm{C} \ldots 150^{\circ} \mathrm{C}$ | 50 Kelvin | $<0.85^{\circ}$ |  |
| $>135^{\circ} \mathrm{C}$ | On | 15 Kelvin | $<3.3^{\circ}$ |

As the magnetic field decreases with higher temperatures, angle errors due to increases of temperature are more critical than decreases of temperature. As the additional angle error described in the TLE5012B Data Sheet applies to the worst case (temperature increasing), the angle error adder due to decreasing temperature changes will always be smaller.
If a parallel SSC interface is in place, autocalibration can be disabled when a critical case described in Figure 4-4 occurs. A temperature check in the microcontroller can be implemented to disable and enable autocalibration (and thus to reset any wrong minima and maxima) on temperature changes by more than 5 Kelvin during 1.5 revolutions. When autocalibration is disabled the default calibration parameters stored in the laser fuses will be used for the $X$ and $Y$ raw values correction, and the angle error will fulfill the specifications described in the TLE5012B Data Sheet.

### 4.2 Prediction mode

The TLE5012B has an optional prediction feature, which serves to reduce the speed dependent angle error in applications where the rotation speed does not change abruptly. Prediction (enable PREDICT bit on MOD_2 register) uses the difference between current and last two angle values to approximate the angle value which will be present after the delay time (see Figure 4-5). The output value is calculated by adding this difference to the measured value, according to Equation (4.1).

$$
\begin{equation*}
\alpha(t+1)=\alpha(t)+\alpha(t-1)-\alpha(t-2) \tag{4.1}
\end{equation*}
$$



Figure 4-5 Delay of sensor output

## Revolution counter on prediction mode

The revolution counter (REVOL bits on AREV register) counts full rotations of the magnetic field. It increments when the measured angle crosses the $0^{\circ}$ point in counter-clockwise rotation direction, and it decrements when the $0^{\circ}$ point is crossed in clockwise rotation direction. The revolution counter always works with the measured angle (current angle and not predicted angle). Therefore, the prediction angle may already indicate that the $0^{\circ}$ has been crossed but the revolution counter may still not increase or decrease if the current calculated angle has not yet changed quadrant. Once the current calculated angle crosses $0^{\circ}$, the revolution counter will be updated. The Figure 4-6 illustrates an example; in the second picture the angle value with prediction has already crossed the $0^{\circ}$ (from $1^{\circ}$ to $359^{\circ}$ ), but the revolution counter has not yet decreased (remains 43 ):


Figure 4-6 Revolution counter with prediction mode disabled/enabled

### 4.3 Calculation of the Junction Temperature

The total power dissipation $P_{\text {TOT }}$ of the chip leads to self-heating, which increases the junction temperature $T_{J}$ above the ambient temperature.
The power multiplied by the total thermal resistance $\mathrm{R}_{\mathrm{thJA}}$ (junction to ambient) yields the junction temperature. $R_{\text {thJA }}$ is the sum of the two components Junction to Case and Case to Ambient.
$R_{t h J A}=R_{t h J C}+R_{t h C A}$
$T_{J}=T_{A}+\Delta T$
$\Delta T=R_{t h J A} \times P_{T O T}=R_{t h J A} \times\left(V_{D D} \times I_{D D}+\sum_{Q} V_{Q} \times I_{Q}\right) \quad\left(\mathrm{IDD}, \mathrm{l}_{\mathrm{Q}}>0\right.$, if direction is into IC)
Example (assuming no load on $\mathrm{V}_{\text {out }}$ ):

$$
\begin{align*}
& V_{D D}=5 V  \tag{4.3}\\
& I_{D D}=14 m A \\
& \Delta T=150\left[\frac{K}{W}\right] \times(5[V] \times 0.014[A]+0[V A])=10.5 \mathrm{~K}
\end{align*}
$$

### 4.4 Calculation of the Temperature

The TLE5012B provides the temperature in the TEMPER bits of the FSYNC register via the SSC interface (see Chapter 6.2) or with an extended SPC frame (see Table 5-8). TEMPER is a compensated value of the temperature at the ADC. The compensation is done with an offset value at $25^{\circ} \mathrm{C}$ temperature (T25O), which is specific for each device. The T25O value is measured for each device during production and it is stored in the fuses.

The temperature in degrees Celsius ( ${ }^{\circ} \mathrm{C}$ ) can be calculated using the formula provided in Chapter 6.2 and reading the TEMPER bits. TEMPER is a signed register, to convert the value to digits proceed as described in Chapter 6.1.3. As an example, for a TEMPER value of $110111000^{\text {B }}$, the value in digits is calculated in Equation (4.4):

$$
\begin{align*}
& \text { Value }=-b_{M S B} * 2^{N-1}+\sum_{i=0}^{N-2} b_{i} * 2^{i}=-1 * 2^{9-1}+1 * 2^{9-2}+0 * 2^{9-3}+1 * 2^{9-4}+1 * 2^{9-5}+  \tag{4.4}\\
& +1 * 2^{9-6}+0 * 2^{9-7}+0 * 2^{9-8}+0 * 2^{9-9}=-1 * 2^{8}+1 * 2^{7}+1 * 2^{5}+1 * 2^{4}+1 * 2^{3}= \\
& =-256+128+32+16+8=-72
\end{align*}
$$

Therefore, the temperature in degrees Celsius is calculated in Equation (4.5):

$$
\begin{equation*}
T\left[{ }^{\circ} \mathrm{C}\right]=\frac{\operatorname{TEMPER}[\mathrm{dig}]+152[\mathrm{dig}]}{2.776\left[\mathrm{dig} /{ }^{\circ} \mathrm{C}\right]}=\frac{-72+152}{2.776}=\frac{80}{2.776}=28.8^{\circ} \mathrm{C} \tag{4.5}
\end{equation*}
$$

TEMPER typical accuracy error is around $+/-5^{\circ} \mathrm{C}$ across the whole temperature range.
TEMPER is a limited register. For a whole temperature range use the T_RAW register, which can be compensated with the T25O register. The relation between TEMPER and T_RAW is shown in Equation (4.6):

$$
\begin{equation*}
T E M P E R[d i g]=T_{-} R A W[\operatorname{dig}]-T 25 O[\operatorname{dig}]-530[\operatorname{dig}] \tag{4.6}
\end{equation*}
$$

### 4.5 Switching to external clock

External clock operation is possible for the interface configurations SSC only, SSC \& PWM, and SSC \& SPC. To switch the TLE5012B to external clock supply the following procedure is used:

- Trigger a chip reset by writing a " 1 " to the AS_RST bit (address 01 $[0]$ ) via SSC interface
- Within $120 \mu$ s after the reset command, write a " 1 " to the CLK_SEL bit (address $06_{H}[4]$ )
- After the power-on time (max. 7 ms ), read the CLK_SEL bit via SSC interface to confirm that external clock is selected

Note: If the clock source (CLK_SEL) bit is switched to external clock during operation of the sensor it may occur (at a chance of roughly 1\%) due to an internal timing conflict, that the switching command is not accepted and the chip keeps operating on internal clock.

## 5 Interfaces

### 5.1 Interfaces overview

The TLE5012B supports five interfaces which can be choosen depending on the specific application:

- SSC (Synchronous Serial Communication)
- PWM (Pulse Width Modulation)
- SPC (Short PWM Code)
- HSM (Hall Switch Mode)
- IIF (Incremental Interface)

SSC: the SSC is a digital interface which allows bi-directional data transfer. The TLE5012B uses 3-pin as described in the Chapter 5.2. SSC allows to read additional data to the angle value from registers (angle speed, raw values, temperature, etc.) and to setup different configurations (resolution, enable/disable of features such as prediction or autocalibration, etc.). Check Chapter 6 for details. SSC allows a high data transfer with CRC (Cyclic Redundancy Check) and secure communication (use of the Safety Word after data transfer). Up to 4 sensors can be used with SSC. SSC is meant for short distances (TLE5012B and ECU to be placed on the same PCB)
PWM: the PWM is an unidirectional interface. Only one line is needed in which the angle value is transmitted. The angle value corresponds to the duty cycle of the signal, with $0^{\circ}$ represented by a $6.25 \%$ duty cycle and $93.75 \%$ representing the maximum angle. Safety Analysis results would be communicatd via duty cycle below $2 \%$ or above $98 \%$. The frequency of the PWM interface can be set via SSC interface. PWM is meant to support distances up to 5 meters.
SPC: the SPC is an interface based on the SENT protocol. The ECU (master $\mu \mathrm{C}$ ) sends a Trigger Nibble which wakes up the TLE5012B to transmit the angle value (12bit or 16bit resolution depending on the number of nibbles). If desired, the temperature can also be transmitted in two extra nibbles. The SPC also sends a CRC and an endpulse to terminate the communication. One line is needed for the transmission and the pins \#1 and \#2 are used to set the slave number. Up to four slaves can be connected to one ECU; the ECU Trigger Nibble length will wake up the respective sensor. SAE International describes the SENT protocol (SAE J2716) distance as up to 5 meters: "Combined resistance for all connector shall have less than 1 Ohms per line over total vehicle life. The bus wiring shall utilize cables with less than $0.1 n F$ per meter of wire length. the maximum cable length shall be 5 meters".

HSM: the HSM is an interface that emulates the output of three Hall switches, therefore three uni-directional lines are required. Only the angle position can be calculated from the output. The switching hysteresis and the pole-pair configuration can be selected via SSC. By default the number of pole pairs is set to 5 .
IIF: the IIF is an interface that emulates an optical encoder. Three uni-directional lines are required: two for Phase $A$ and Phase B and a third one for the IIF Index (which indicates a $0^{\circ}$ pass). Phase A and Phase B pulse out phaseshifted pulses for each "step resolution" that the angle moved. The two Phases are needed to also track the rotation direction (clockwise or counter-clockwise). At start-up the IIF pulses out the angle value. Different IIF modes, step resolutions and hysteresis values can be configurated via SSC. IIF interface is meant for short distances (TLE5012B and ECU to be placed on the same PCB). It is used for high-speed applications such as electrically commutated motor drives.

SSC can be used in parallel to any other interface (PWM, SPC, HSM or IIF).

More details on the default configuration of each derivate are described in Chapter 7.

Table 5-1 summarizies the key characteristics and parameters that have to be considered when choosing an interface:

Table 5-1 Main interface characteristics

| Characteristics | IIF | PWM | SPC | HSM | SSC |
| :---: | :---: | :---: | :---: | :---: | :---: |
| Data/Values | angle steps (angle value at start-up) | angle value | angle value (temperature optional) | angle value period | many data available in the registers |
| Distance ${ }^{1)}$ | short-medium | long (up to 5m) | long (up to 5m) | medium | short |
| Data rate | high | low-medium | low | high | high |
| Resolution | high | high | high | low | high |
| Check | IIF Index ( $0^{\circ}$ pulse). Phase A/B as complementary signal. | Duty cycle range diagnostics. | CRC | HS1/HS2/HS3 as complementary signals. | Safety Word in the data transfer. Availability of status and diagnostics registers. |
| Max. slaves in bus mode | no bus mode | no bus mode | 4 | no bus mode | 4 |
| Communication lines ${ }^{2)}$ | 3 (only two without IIF Index) | 1 | 1 | 3 | 3 |
| Communication | unidirectional | unidirectional | unidirectional (triggered) | unidirectional | bidirectional |
| SSC possible | Yes | Yes | Yes | Yes | Yes |
| Other | Emulates Optical Encoder |  | Based on SENT protocol | Emulates (three) Hall Switches | 3-wire SPI |

1) Not subject to production test. Distance subject to application circuit and environment.
2) Communication lines between slave (TLE5012B) and master (microcontroller). External clock not included

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### 5.2 Synchronous Serial Communication (SSC) Interface

### 5.2.1 SSC Timing Definition



Figure 5-1 SSC timing

## SSC Inactive Time ( $C S_{\text {off }}$ )

The SSC inactive time defines the delay time after a transfer before the TLE5012B can be selected again.

Table 5-2 SSC push-pull timing specification

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Typ. | Max. |  |  |
| SSC baud rate | $\mathrm{f}_{\text {Ssc }}$ |  | 8.0 |  | Mbit/s | 1) |
| CSQ setup time | $\mathrm{t}_{\mathrm{CSs}}$ | 105 |  |  | ns | 1) |
| CSQ hold time | $\mathrm{t}_{\mathrm{CSh}}$ | 105 |  |  | ns | 1) |
| CSQ off | $\mathrm{t}_{\text {CSoff }}$ | 600 |  |  | ns | SSC inactive time ${ }^{1)}$ |
| SCK period | $\mathrm{t}_{\text {SCKp }}$ | 120 | 125 |  | ns | 1) |
| SCK high | $\mathrm{t}_{\text {SCKh }}$ | 40 |  |  | ns | 1) |
| SCK low | $\mathrm{t}_{\text {SCKI }}$ | 30 |  |  | ns | 1) |
| DATA setup time | $\mathrm{t}_{\text {DATAs }}$ | 25 |  |  | ns | 1) |
| DATA hold time | $\mathrm{t}_{\text {DATAh }}$ | 40 |  |  | ns | 1) |
| Write read delay | $\mathrm{t}_{\text {wr_delay }}$ | 130 |  |  | ns | 1) |
| Update time | $\mathrm{t}_{\text {CSupdate }}$ | 1 |  |  | $\mu \mathrm{s}$ | See Figure 5-5 ${ }^{1)}$ |
| SCK off | $\mathrm{t}_{\text {SCKoff }}$ | 170 |  |  | ns | 1) |

1) Not subject to production test - verified by design/characterization

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Table 5-3 SSC open-drain timing specification

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Typ. | Max. |  |  |
| SSC baud rate | $\mathrm{f}_{\text {SSC }}$ |  | 2.0 |  | Mbit/s | Pull-up Resistor $=1 \mathrm{k} \Omega^{1)}$ |
| CSQ setup time | $\mathrm{t}_{\mathrm{CSs}}$ | 300 |  |  | ns | 1) |
| CSQ hold time | $\mathrm{t}_{\text {CSh }}$ | 400 |  |  | ns | 1) |
| CSQ off | $\mathrm{t}_{\text {CSoff }}$ | 600 |  |  | ns | SSC inactive time ${ }^{1)}$ |
| SCK period | $\mathrm{t}_{\text {SCKp }}$ | 500 |  |  | ns | 1) |
| SCK high | $\mathrm{t}_{\text {SCKh }}$ |  | 190 |  | ns | 1) |
| SCK low | $\mathrm{t}_{\text {SCKI }}$ |  | 190 |  | ns | 1) |
| DATA setup time | $\mathrm{t}_{\text {DATAs }}$ | 25 |  |  | ns | 1) |
| DATA hold time | $\mathrm{t}_{\text {DATAh }}$ | 40 |  |  | ns | 1) |
| Write read delay | $\mathrm{t}_{\text {wr_delay }}$ | 130 |  |  | ns | 1) |
| Update time | $\mathrm{t}_{\text {CSupdate }}$ | 1 |  |  | $\mu \mathrm{S}$ | See Figure 5-5 ${ }^{1 \text { 1 }}$ |
| SCK off | $\mathrm{t}_{\text {SCKoff }}$ | 170 |  |  | ns | 1) |

1) Not subject to production test - verified by design/characterization

### 5.2.2 SSC Data Transfer

The SSC data transfer is word-aligned. The following transfer words are possible:

- Command Word (to access and change operating modes of the TLE5012B)
- Data words (any data transferred in any direction)
- Safety Word (confirms the data transfer and provides status information)


Figure 5-2 SSC data transfer (data-read example)


Figure 5-3 SSC data transfer (data-write example)

## Command Word

SSC Communication between the TLE5012B and a microcontroller is generally initiated by a command word. The structure of the command word is shown in Table 5-4, where the Update (UPD) bit allows the access to current values or updated values. If an update command is issued and the UPD bit is set, the immediate values are stored in the update buffer simultaneously. This enables a snapshot of all necessary system parameters at the same time. Bits with an update buffer are marked by an " $u$ " in the Type column in register descriptions. The initialization of such an update is described on page 35 .

Table 5-4 Structure of the Command Word

| Name | Bits | Description |
| :--- | :--- | :--- |
| RW | $[15]$ | Read -Write <br> $0:$ Write <br> $1:$ Read |
| Lock | $[14 . .11]$ | 4-bit Lock Value <br> $0000_{\mathrm{B}}:$ Default operating access for addresses $0 \times 00: 0 \times 04,0 \times 14: 0 \times 15,0 \times 20$, <br> $0 \times 30$ <br> $1010_{\mathrm{B}}:$ Configuration access for addresses $0 \times 05: 0 \times 11$ |

Table 5-4 Structure of the Command Word (cont'd)

| Name | Bits | Description |
| :--- | :--- | :--- |
| UPD | $[10]$ | Update-Register Access <br> $0:$ Access to current values <br> $1:$ Access to values in update buffer |
| ADDR | $[9 . .4]$ | 6-bit Address |
| ND | $[3 . .0]$ | 4-bit Number of Data Words (if bits set to $0000_{B}$, no safety word is provided) |

## Safety Word

The safety word consists of the following bits:

Table 5-5 Structure of the Safety Word

| Name | Bits | Description |
| :--- | :--- | :--- |
| STAT $^{1)}$ | Chip and Interface Status |  |

1) When an error occurs, the corresponding status bit in the safety word remains "low" until the STAT register (address $00_{\mathrm{H}}$ ) is read via SSC interface. Once the STAT register has been read, the safety word status bits will be "high" again.

## Bit Types

The types of bits used in the registers are listed here:

Table 5-6 Bit Types

| Abbreviation | Function | Description |
| :--- | :--- | :--- |
| r | Read | Read-only registers |
| w | Write | Read and write registers |
| u | Update | Update buffer for this bit is present. If an update is issued and the Update- <br> Register Access bit (UPD in command word) is set, the immediate values are <br> stored in this update buffer simultaneously. This allows a snapshot of all <br> necessary system parameters at the same time. |

## Data communication via SSC



Figure 5-4 SSC bit ordering (read example)


Figure 5-5 Update of update registers
The data communication via SSC interface has the following characteristics:

- The data transmission order is Most-Significant Bit (MSB) first, Least-Significant Bit (LSB) last.
- Data is put on the data line with the rising edge of SCK and read with the falling edge of SCK.
- The SSC Interface is word-aligned. All functions are activated after each transmitted word.
- After every data transfer with ND $\geq 1$, the 16 -bit Safety Word is appended by the TLE5012B.
- A "high" condition on the Chip Select pin (CSQ) of the selected TLE5012B interrupts the transfer immediately. The CRC calculator is automatically reset.
- After changing the data direction, a delay $t_{\text {wr_delay }}$ (see Table 5-3) has to be implemented before continuing the data transfer. This is necessary for internal register access.
- If in the Command Word the number of data is greater than 1 (ND $>1$ ), then a corresponding number of consecutive registers is read, starting at the address given by ADDR.
- In case an overflow occurs at address $3 \mathrm{~F}_{\mathrm{H}}$, the transfer continues at address $00_{\mathrm{H}}$.
- If in the Command Word the number of data is zero ( $N D=0$ ), the register at the address given by ADDR is read, but no Safety Word is sent by the TLE5012B. This allows a fast readout of one register.
- At a rising edge of CSQ without a preceding data transfer (no SCK pulse, see Figure 5-5), the content of all registers which have an update buffer is saved into the buffer. This procedure serves to take a snapshot of all relevant sensor parameters at a given time. The content of the update buffer can then be read by sending a read command for the desired register and setting the UPD bit of the Command Word to " 1 ".
- After sending the Safety Word, the transfer ends. To start another data transfer, the CSQ has to be deselected once for at least $\mathrm{t}_{\text {csoff }}$.
- By default, the SSC interface is set to push-pull. The push-pull driver is active only if the TLE5012B has to send data, otherwise the DATA pin is set to high-impedance.


### 5.2.3 TLE5012B in bus mode

Up to four slaves can be connected on the same bus (e.g. four TLE5012B, or two TLE5012B and two Linear Hall). The master microcontroller ( $\mu \mathrm{C}$ ) will need four CSQ (chip select) pins to connect to each of the slaves (Daisy Chain schemes are not possible).


Figure 5-6 Example of four slaves connected to a bus with one master with SSC interface
The TLE5012B particularity is that it is a 3-pin SSC (SPI) slave. One of these pins is for the Clock, another one is for the Chip Select and the third one is for the Data (input and output). Since there is only one pin for the Data, the output and input of the master have to be connected. When the sensor transmits data the master's output pin (SDO pin) has to be switched to high ohmic.

## Clock generation

As described in Chapter 5.2.1 the master has to send a command word to start the communication between master and slave. After that, the master has to trigger a clock so the slave can respond with the data and/or safety word. To generate a clock set the direction of the master's SDO pin to input and next write 0xFFFF in the SDO register. A delay $t_{\text {wr_delay }}$ (see Table 5-2) has to be implemented before generating the clock for the answer.
With this a pulse of " 1 s " is generated and the clock triggered. Since the SDO has been set as an input pin, this pulse of "1s" will not be transmitted and will not interefere with the data coming from the slave (sensor). This step (writing 0xFFFF) has to be repeated as many times as reads from the slave are expected. This is usually twice; one for the data and one for the safety word.

## Slave Number configuration at start-up

With SSC the CSQ line ensures that the data sent -or received- goes to -or comes from- the correct slave. Still, if the slave number (S_NR bits) are not configurated correctly at start-up, the safety word may report a wrong slave number. The slave number may also be wrong in configurations with one single slave.

To ensure that the received slave number in the safety word is correct (RESP bits), configure the slave numbers at start up with a write command. The slave number bits are described in the Status Register.
For configurations with only one or two slaves, it is also possible to configure the slave number at start up with the SCK and IFC pins as done for the SPC interface (see Figure 5-12). The particularity with SSC interface is that the SCK is a line connected to the master and therefore can only have on status at start-up. Setting the IFC pin at "high" or "low" two slave numbers can be configurated.

### 5.2.4 Cyclic Redundancy Check (CRC)

A Cyclic Redundancy Check (CRC) is sent in the last 8 bits of the safety word.

- This CRC is according to the J1850 Bus Specification.
- Every new transfer restarts the CRC generation.
- The Command Word and all Data Words (in any direction) will be taken into account to generate the CRC. The non-CRC bits -the 8 upper bits- of the safety word).
- Generator polynomial: $X 8+X 4+X 3+X 2+1$, but for the $C R C$ generation the fast-CRC generation circuit is used (see Figure 5-7)
- The seed value of the fast CRC circuit is ' $111111111_{B}$ '.
- The remainder is inverted before transmission.


Figure 5-7 Fast CRC polynomial division circuit

## CRC calculation example with SSC interface

In this example the CRC generation for a typical SSC data transfer is shown. In this case the feature Prediction will be enabled, so the SSC data transfer consists of a command word and a write data word send by the master (microcrontroller) followed by a safety word -which contains the CRC- send by the slave (TLE5012B).

The command word $5081_{H}$ indicates that a write data word (MSB of the command word at " 0 ") will follow and that this data has to be written in the address 08 H $_{\text {( }}^{2}$ (MOD_2 register). The four LSBs of the command Word indicate how many 16-bit words will follow ("0001B" in this case).
The write word $0804_{H}$ is sent to enable Prediction, one of the features available with the TLE5012B. The PREDICT bit (bit 2 of the WRITE Data 1) will be set at " 1 ".
Note: Before sending a Write Data, it is necessary to receive a Read Data to ensure that the bits that will not be configurated (changed) are not overwritten with a wrong value (e.g. read-modify-write operation).

After writing the new configuration parameters, the sensor will send a safety word FE89 ${ }_{H}$ indicating the status (STAT), the sensor number (RESP, " 1110 " in this case since there is only one sensor named " 00 ") and the CRC (STAT and RESP are not included in its generation). In this case the CRC transmitted is $89_{\mathrm{H}}$.

## CRC generation

At the beginning the CRC is set at $00_{\mathrm{H}}$ (see Figure 5-9, line 1). The first step to generate the CRC consists in a XOR logical operation (line 3) between the 8 MSB bits of the Command Word (line 1) and the seed value 11111111 (line 2). Align the generator polynominal (line 4) to the non-zero MSB of the dataset out of the first step (line 3) and calculate another XOR (line 5).


Figure 5-8 TLE5012B's CRC generator polynomial for the SSC interface
From this point onwards reiterative XOR logical operations between the data (result of the previous operation) and the generator polynominal are done till the remaining bits is equal or smaller than $00 \mathrm{FF}_{\mathrm{H}}$ (only 8 bits left). The
genarator polynomial always has to be aligned to the non-zero MSB of the dataset. Finally the CRC value (line 33) has to be inverted (XOR with a all "1"s polynominal) to generate the Inverted Remainder (line 34).


Figure 5-9 CRC generation example with SSC interface

## CRC generation software code example

Two software codes with C-language to generate CRC are provided. The first example is a more intuitive though slower solution, since two iterative loops are done; a loop for each byte and an inner loop for each bit. It is also a compact solution.
The second code is faster, since the inner loop is implemented as a look-up table (LUT). Therefore, the CRC does not need to be calculated each time, but is taken from the look-up table, saving some computational time. As a look-up table is required, some extra memory space is needed compared to the first example.

## Example 1:

```
//"message" is the data transfer for which a CRC has to be calculated.
//A typical "message" consists of 2 bytes for the command word plus 2 bytes for the
//data word plus 2 bytes for the safety word.
//"Bytelength" is the number of bytes in the "message". A typical "message" has 6
//bytes.
unsigned char CRC8(unsigned char *message, unsigned char Bytelength)
```

\{
//"crc" defined as the 8-bits that will be generated through the message till the
//final crc is generated. In the example above this are the blue lines out of the
//XOR operation.
unsigned char crc;

```
//"Byteidx" is a counter to compare the bytes used for the CRC calculation
    unsigned char Byteidx, Bitidx;
//Initially the CRC remainder has to be set with the original seed (OxFF for the
//TLE5012B).
    crc = 0xFF;
//For all the bytes of the message.
    for(Byteidx=0; Byteidx<Bytelength; Byteidx++)
    {
//"crc" is calculated as the XOR operation from the previous "crc" and the "message".
//"^" is the XOR operator.
    crc ^^ message[Byteidx];
//For each bit position in a 8-bit word
    for(Bitidx=0; Bitidx<8; Bitidx++)
    {
//If the MSB of the "crc" is 1(with the &0x80 mask we get the MSB of the crc).
            if((crc&0x80)!=0)
        {
//"crc" advances on position ("crc" is moved left 1 bit: the MSB is deleted since it
//will be cancelled out with the first one of the generator polynomial and a new bit
//from the "message" is taken as LSB.)
        crc <<=1;
//"crc" is calculated as the XOR operation from the previous "crc" and the generator
//polynomial (0x1D for TLE5012B). Be aware that here the x8 bit is not taken since
//the MSB of the "crc" already has been deleted in the previous step.
        crc ^= 0x1D;
        }
```

```
//In case the crc MSB is 0.
    else
//"crc" advances one position (this step is to ensure that the XOR operation is only
//done when the generator polynomial is aligned with a MSB of the message that is " }1\mathrm{ ".
        crc <<= 1;
        }
    }
```

//Return the inverted "crc" remainder("~" is the invertion operator). An alternative
//to the "~" operator would be a XOR operation between "crc" and a 0xFF polynomial.
return (~crc);
\}

## Example 2:

## The function that generates the CRC:

//"message" is the data transfer for which a CRC has to be calculated.
//A typical "message" consists of 2 bytes for the command word plus 2 bytes for the //data word plus 2 bytes for the safety word.
//"Bytelength" is the number of bytes in the "message". A typical "message" has 6 / /bytes.
//*Table CRC is the pointer to the look-up table (LUT)
unsigned char CRC8 (unsigned char *message, unsigned char Bytelength, unsigned char * TableCRC)
\{
//"crc" defined as the 8-bits that will be generated through the message till the //final crc is generated. In the example above this are the blue lines out of the //XOR operation.
unsigned char crc;

```
//"Byteidx" is a counter to compare the bytes used for the CRC calculation and
//"Bytelength".
    unsigned char Byteid;
//Initially the CRC remainder has to be set with the original seed (OxFF for the
//TLE5012B).
    crc = 0xFF;
//For all the bytes of the message.
    for(Byteidx=0; Byteidx<Bytelength; Byteidx++)
    {
//"crc" is the value in the look-up table TableCRC[x] at the position "x".
//The position "x" is determined as the XOR operation between the previous "crc" and
//the next byte of the "message".
//"^" is the XOR operator.
    crc = TableCRC[crc ^ *(message+Byteidx)];
    }
//Return the inverted "crc" remainder("~" is the invertion operator). An alternative //to the "~" operator would be a XOR operation between "crc" and a 0xFF polynomial.
```

```
    return(~crc);
}
The look-up table -which depends on the CRC generator polynomial- required for the TLE5012B is as follows:
//Look-up table (LUT) for the TLE5012B with generator polynomial 100011101 (0x11D).
//As this table will be checked byte by byte, each byte has 256 possible values (2^8)
//for its CRC calculation with the given generator polynomial.
unsigned char TableCRC[256]
{
//The "crc" of the position [1] (result from operation [crc ^*(message+Byteidx)])
//is 0x00 -> 0x00 XOR 0x11D = 0x00 (1 byte).
    0x00,
//The "crc" of the position [2] is 0x1D -> 0x01 XOR 0x11D = 0x1D (1 byte).
    0x1D,
//The "crc" of the position [3] is 0x3A -> 0x02 XOR 0x11D = 0x3A (1 byte).
    0x3A,
//For all the rest of the cases.
    0x27, 0x74, 0x69, 0x4E, 0x53, 0xE8, 0xF5, 0xD2, 0xCF, 0x9C, 0x81, 0xA6, 0xBB, 0xCD,
    0xD0, 0xF7, 0xEA, 0xB9, 0xA4, 0x83, 0x9E, 0x25, 0x38, 0x1F, 0x02, 0x51, 0x4C, 0x6B,
    0x76, 0x87, 0x9A, 0xBD, 0xA0, 0xF3, 0xEE, 0xC9, 0xD4, 0x6F, 0x72, 0x55, 0x48, 0x1B,
    0x06, 0x21, 0x3C, 0x4A, 0x57, 0x70, 0x6D, 0x3E, 0x23, 0x04, 0x19, 0xA2, 0xBF, 0x98,
    0x85, 0xD6, 0xCB, 0xEC, 0xF1, 0x13, 0x0E, 0x29, 0x34, 0x67, 0x7A, 0x5D, 0x40, 0xFB,
    0xE6, 0xC1, 0xDC, 0x8F, 0x92, 0xB5, 0xA8, 0xDE, 0xC3, 0xE4, 0xF9, 0xAA, 0xB7, 0x90,
    0x8D, 0x36, 0x2B, 0x0C, 0x11, 0x42, 0x5F, 0x78, 0x65, 0x94, 0x89, 0xAE, 0xB3, 0xE0,
    0xFD, 0xDA, 0xC7, 0x7C, 0x61, 0x46, 0x5B, 0x08, 0x15, 0x32, 0x2F, 0x59, 0x44, 0x63,
    0x7E, 0x2D, 0x30, 0x17, 0x0A, 0xB1, 0xAC, 0x8B, 0x96, 0xC5, 0xD8, 0xFF, 0xE2, 0x26,
    0x3B, 0x1C, 0x01, 0x52, 0x4F, 0x68, 0x75, 0xCE, 0xD3, 0xF4, 0xE9, 0xBA, 0xA7, 0x80,
    0x9D, 0xEB, 0xF6, 0xD1, 0xCC, 0x9F, 0x82, 0xA5, 0xB8, 0x03, 0x1E, 0x39, 0x24, 0x77,
    0x6A, 0x4D, 0x50, 0xA1, 0xBC, 0x9B, 0x86, 0xD5, 0xC8, 0xEF, 0xF2, 0x49, 0x54, 0x73,
    0x6E, 0x3D, 0x20, 0x07, 0x1A, 0x6C, 0x71, 0x56, 0x4B, 0x18, 0x05, 0x22, 0x3F, 0x84,
    0x99, 0xBE, 0xA3, 0xF0, 0xED, 0xCA, 0xD7, 0x35, 0x28, 0x0F, 0x12, 0x41, 0x5C, 0x7B,
    0x66, 0xDD, 0xC0, 0xE7, 0xFA, 0xA9, 0xB4, 0x93, 0x8E, 0xF8, 0xE5, 0xC2, 0xDF, 0x8C,
    0x91, 0xB6, 0xAB, 0x10, 0x0D, 0x2A, 0x37, 0x64, 0x79, 0x5E, 0x43, 0xB2, 0xAF, 0x88,
    0x95, 0xC6, 0xDB, 0xFC, 0xE1, 0x5A, 0x47, 0x60, 0x7D, 0x2E, 0x33, 0x14, 0x09, 0x7F,
    0x62, 0x45, 0x58, 0x0B, 0x16, 0x31, 0x2C, 0x97, 0x8A, 0xAD, 0xB0, 0xE3, 0xFe,
//The "crc" of the position [255] is 0xD9 -> 0xFE XOR 0x11D = 0xD9 (1 byte).
    0xD9,
//The "crc" of the position [256] is 0xC4 -> 0xFF XOR 0x11D = 0xC4 (1 byte).
    0xC4
}
```

The following code does not need to be implemented since the look-up table is already provided above. But for general interest the following code would be used to generate the look-up table independently of which generator polynomial is used. This code can also be used to ensure that the values in the look-up table are correctly generated/copied to the application.

```
//Generation of a look-up table (LUT)
void BuildCRCTable(unsigned int polynomial, unsigned char * crcTable)
{
```

//"ReducedPoly" is the generator polynomial

```
unsigned char ReducedPoly;
unsigned int message;
unsigned char crc;
unsigned bitindex;
//Only 8 bits are taken
    ReducedPoly = (unsigned char)(polynomial&0x00FF);
//For all the possible "message" combinations
    for (message=0; message <= 0xFF; message++)
    {
        crc=(unsigned char)message;
//For all the bits of the byte.
        for(Bitindex=0; Bitindex<8; Bitindex++)
        {
//Calculation of the CRC
        if((crc&0x80)!=0)
        {
            crc <<= 1;
            crc ^= ReducedPoly;
        }
        else
            crc <<=1;
        }
//The value out of the CRC calculation for a certain "message" is saved in the
//position of the "message".
    *(crcTable+message) = crc;
    }
}
```


## Disclaimer

The CRC generation software code provided above shall be used as guidance to the developer of solutions with the TLE5012B. Infineon is not responsible for malfunctioning of the code provided above. This code was used with an Infineon's microcontroller XC878.

- The CRC generation software code is only provided as a hint for the implementation or the use of the Infineon Technologies components and shall not be regarded as any description or warrant of a certain functionalities, conditions or quality of the Infineon Technologies component(s).
- All statements contained in this code, including recommendation or suggestion or methodology, are to be verified by the user before implementation or use, as operating conditions and environmental factors may differ. The recipient of this code must verify any function described herein in the real application.
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### 5.2.5 Angle Calculation with X-raw and Y-raw values

The TLE5012B's COordinate Rotation Dlgital Computer (CORDIC) contains the trigonometric function for angle calculation. The angle value can be accessed reading the ANG_VAL register.
For safety checks and other purposes, it is also possible to calculate the angle value in a microcontroller by reading the X -raw and Y -raw values from the TLE5012B. The raw values have to be compensated by either calculating the offset, amplitude and phase parameters or by reading the registers which contain the pre-calibrated values. The second case is recommended in cases where either the application does not turn full rotations (to calculate the compensation parameters the whole sine and cosine signals are required) or it rotates at high speeds (enough data has to be read to ensure that the maximum and minimum values of the sine and cosine are read).

### 5.2.5.1 Angle Calculation using pre-calibrated compensation values

For the angle calculation using pre-calibrated compensation values the following values have to be read from the registers:

- X-raw value (ADC_X register, address $10_{\mathrm{H}}$ )
- Y-raw value (ADC_Y register, address $11_{\mathrm{H}}$ )
- T-raw value (T_RAW register, address $15_{\mathrm{H}}$ )
- T25O value (T25O register, address $30_{\mathrm{H}}$ )
- TCO_X_T value (MOD_4 register, address $0 \mathrm{E}_{\mathrm{H}}$ )
- TCO_Y_T value (TCO_Y register, address $0 \mathrm{~F}_{\mathrm{H}}$ )
- X_OFFSET value (Offset $X$ register, address $0 A_{H}$ )
- Y_OFFSET value (Offset $Y$ register, address $0 B_{H}$ )
- SYNCH value (SYNCH register, address $0 C_{H}$ )
- ORTHO value (IFAB register, address $0 D_{H}$ )
- ANG_BASE value (MOD_3 register, address 09 ${ }_{\mathrm{H}}$ )

The values T25O, TCO_X_T, TCO_Y_T, X_OFFSET, Y_OFFSET, SYNCH, ORTHO and ANG_BASE are values specific for each device and constant (if autocalibration disabled). Therefore these values are required to be read only once and saved to the microcontroller for re-use.
Refer to Chapter 6.2 for the description of the listed registers. These values have to be read with autocalibration disabled.

## X-raw and $Y$-raw values compensation

To increase the accuracy, the temperature-dependent offset drift can be compensated. The offset values $\mathrm{O}_{\mathrm{X}}$ and $\mathrm{O}_{\mathrm{Y}}$ can be described by Equation (5.1):

$$
\begin{align*}
& O_{X}=X_{-} O F F S E T+T C O_{-} X_{-} T^{*}\left(T_{-} R A W-T 25 O-439\right) \\
& O_{Y}=Y Y_{-} O F F S E T+T C O_{-} Y{ }_{-} T^{*}\left(T_{-} R A W-T 25 O-439\right) \tag{5.1}
\end{align*}
$$

T25O is a 7 bit register that has to be subtracted from the 10 bit T_RAW register. No shifts are required in this operation, since the higher order bits of the T_RAW register are used to represent a wider range of values and not a different resolution.
TCO_X_T and TCO_Y_T have 7 bits only and are multiplied with a 10 bit value. Therefore the result of the multiplication has to be limited to the 10 MSBs (arithmetic shift by 7 , if supported by compiler/architecture or signed division by 128). In the last step of Equation (5.1), the 10 bit value for the temperature-dependent offset has to be added to the 12 bit $X$ _OFFSET and $Y$ _OFFSET.

After the $X$ and $Y$ values are read out, the temperature-corrected offset value must be subtracted:

$$
\begin{align*}
& X_{1}=X_{-} R A W-O_{X} \\
& Y_{1}=Y_{-} R A W-O_{Y} \tag{5.2}
\end{align*}
$$

$X \_R A W$ and $Y \_R A W$ are 16 bit values at which a 12 bit value is subtracted. Offsets are in the 12 bit range since the values are smaller than the whole $X \_R A W$ and $Y$ _RAW range.
Next, the $Y$ value is normalized with the amplitude synchronicity:

$$
\begin{align*}
& X_{2}=X_{1} \\
& Y_{2}=Y_{1} * S Y N C H \tag{5.3}
\end{align*}
$$

While $Y_{1}$ is a 16 bit absolute value, SYNCH is a 12 bit relative factor (amplitude synchronicity is a relative correction between the amplitude of the X-raw and Y-raw values). To convert SYNCH to absolute factor a normalized one has to be added, this corresponds to add a value of 16,384 (2^14). After the multiplication $Y_{2}$ will be a 28 bit value (16 bit from $Y_{1}$ and 14 bit from the SYNCH absolute factor which includes the added one), therefore it has to be shifted to have the 16 MSBs only (arithmetic shift by 14, if supported by compiler/architecture or signed division by 16384).
The influence of the non-orthogonality can be compensated using the following equation, in which only the $Y$ value must be corrected:

$$
\begin{align*}
& X_{3}=X_{2} \\
& Y_{3}=\frac{Y_{2}-X_{2} * \sin (- \text { ORTHO })}{\cos (- \text { ORTHO })} \tag{5.4}
\end{align*}
$$

As described in the IFAB register (address $0 D_{H}$ ), the ORTHO bits represent a value between $-11.2500^{\circ}$ and $11.2445^{\circ}$ with a 12 bit resolution. $Y_{3}$ should finally be limited to 16 bits.

## Angle calculation

After correction of all errors, the resulting angle can be calculated using the arctan function and subtracting the angle base as shown in Equation (5.5):

$$
\begin{equation*}
\alpha=\arctan \left(\frac{Y_{3}}{X_{3}}\right)-A N G-B A S E \tag{5.5}
\end{equation*}
$$

To correctly resolve the arctan function in $360^{\circ}$, the microcontroller should implement the function $\arctan 2\left(Y_{3} / X_{3}\right)$. ANG_BASE is a 12 bit register.

Small deltas from the ANG_VAL register may depend on the speed of application.
Figure 5-10 shows the flow chart of angle calculation from the X -raw and Y -raw values as described above.


Figure 5-10 Flow-Chart of Angle Calculation from the X -raw and Y -raw values

### 5.2.5.2 Angle Calculation with end-of-line calibration values

The TLE5012B already has pre-calibrated compensation parameters which can be used to calculate the angle value (see Chapter 5.2.5.1). Own compensation parameters can also be calculated end-of-line if desired. In that case check the Application Note TLE5009 Calibration.

### 5.3 Pulse Width Modulation Interface

The Pulse Width Modulation (PWM) interface can be selected via SSC (IF_MD = '01') in the register MOD_4.
The PWM update rate can be programmed within the register $0 E_{H}$ (IFAB_RES) in four possible steps with 12-bit resolution (including diagnostics):

- $\sim 0.25 \mathrm{kHz}$
- $\sim 0.5 \mathrm{kHz}$
- $\sim 1.0 \mathrm{kHz}$
- $\sim 2.0 \mathrm{kHz}$

PWM uses a square wave with constant frequency whose duty cycle is modulated according to the last measured angle value (AVAL register).

Figure 5-11 shows the principal behavior of a PWM with various duty cycles and the definition of timing values. The duty cycle of a PWM is defined by the following general formulas:

$$
\begin{align*}
& \text { Duty Cycle }=\frac{t_{o n}}{t_{P W M}} \\
& t_{P W M}=t_{o n}+t_{o f f} \\
& f_{P W M}=\frac{1}{t_{P W M}} \tag{5.6}
\end{align*}
$$

The duty cycle range between 0-6.25\% and 93.75-100\% is used only for diagnostic purposes. In case the sensor detects an error, the corresponding error information will be transmitted by the PWM duty cycle, either in the lower ( $0-6.25 \%$ ) or upper ( $93.75-100 \%$ ) diagnostic range, depending on the kind of error (see "Output duty cycle range" in Table 5-7). As long as a fault is present, the error information will be transmitted in PWM frames. This diagnostic function can be disabled via the MOD_4 register (see Chapter 6.2).
Sensors with preset PWM are available as TLE5012B E5xxx. The register settings for these sensors can be found in Chapter 6.2.


Figure 5-11 Typical example of a PWM signal

Table 5-7 PWM interface

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Typ. | Max. |  |  |
| PWM output frequencies (Selectable by IFAB_RES) | $\mathrm{f}_{\text {PWM } 1}$ | 232 | 244 | 262 | Hz | 1) |
|  | $\mathrm{f}_{\text {PWM } 2}$ | 464 | 488 | 525 | Hz | 1) |
|  | $\mathrm{f}_{\text {PWM }}$ | 929 | 977 | 1050 | Hz | 1) |
|  | $\mathrm{f}_{\text {PWM4 }}$ | 1855 | 1953 | 2099 | Hz | 1) |
| Output duty cycle range | DY ${ }_{\text {PWM }}$ | 6.25 |  | 93.75 | \% | Absolute angle ${ }^{1)}$ |
|  |  |  | 2 |  | \% | Electrical Error (S_RST; $\text { S_VR( }{ }^{122)}$ |
|  |  |  | 98 |  | \% | $\begin{aligned} & \text { System error (S_FUSE; } \\ & \text { S_OV; S_XYOL; } \\ & \text { S_MAGOL; S_ADCT) }{ }^{1)} \end{aligned}$ |
|  |  | 0 |  | 1 | \% | Short to GND ${ }^{1}$ |
|  |  | 99 |  | 100 | \% | Short to $\mathrm{V}_{\mathrm{DD}}$, power loss ${ }^{1)}$ |

1) Not subject to production test - verified by design/characterization
2) Both hardware and software resets will generate an Electrical Error duty cycle for the first PWM pulse after the reset (S_RST). After readout, S_RST bit will be set to " 0 ", so the second PWM pulse will indicate an angle.

The PWM frequency is derived from the digital clock via

$$
\begin{equation*}
f_{\mathrm{PWM}}=\frac{f_{\mathrm{DIG}} * 2^{\text {IFAB_RES }}}{24 * 4096} \tag{5.7}
\end{equation*}
$$

The min/max values given in Table 5-7 take into account the internal digital clock variation specified in TLE5012B Data Sheet. If external clock is used, the variation of the PWM frequency can be derived from the variation of the external clock using Equation (5.7).

## Pulse length convertion to angle value

The length of the duty cycle represents the angle value. Whatever the absolute angle value is, the $t_{\text {on }}$ time depends on the angle value calculated by the TLE5012B with resolution up to $0.100^{\circ}$. The $0.100^{\circ}$ resolution is due to the fact that with 12bit resolution ( 4096 steps) $100 \%$ of the duty cycle can be mapped, but only $87.5 \%$ of the duty cycle translates to angle values. This means that the $360^{\circ}$ degees must be mapped with only 3584 steps ( $87.5 \%^{*} 4096$ ), so effective resolution is $0.100^{\circ}$.

The angle value can be measured with the following formula, where $t_{\mathrm{ON}}$ is the length of the pulse in seconds and $\mathrm{f}_{\mathrm{PWM}}$ is the frequency selected:

$$
\begin{equation*}
\text { Angle }\left[^{\circ}\right]=\left(t_{O N}-6.25 \% * \frac{1}{f_{P W M}}\right) * \frac{360^{\circ}}{87.5 \% * \frac{1}{f_{P W M}}} \tag{5.8}
\end{equation*}
$$

The frequency for the PWM interface can be selected via the register MOD_4 (IFAB_RES bits) as described in Chapter 6.2.1. See Chapter 7 for the PWM derivates with the default frequencies.
A $\mathrm{t}_{\mathrm{ON}}$ of more than $93.75 \%$ duty cycle would indicate an error as described in Table 5-7.

### 5.4 Short PWM Code (SPC)

The Short PWM Code (SPC) is a synchronized data transmission based on the SENT protocol (Single Edge Nibble Transmission) defined by SAE J2716. As opposed to SENT, which implies a continuous transmission of data, the SPC protocoll transmits data only after receiving a specific trigger pulse from the microcontroller. The required length of the trigger pulse depends on the sensor number, which is configurable. Thereby, SPC allows the operation of up to four sensors on one bus line.
SPC enables the use of enhanced protocol functionality due to the ability to select between various sensor slaves (ID selection). The slave number (S_NR) can be given by the external circuit of SCK and IFC pin. In case of $V_{D D}$ on SCK, the S_NR[0] can be set to 1 and in the case of GND on SCK the S_NR[0] is equal to 0 . S_NR[1] can be adjusted in the same way by the IFC pin. Only one data line to the slaves is necessary, as the length of the trigger nibble will awake one or the other slaves, as explained in the next paragraph.


Figure 5-12 Example of four slaves connected to a bus with one master with SPC interface
As in SENT, the time between two consecutive falling edges defines the value of a 4-bit nibble, thus representing numbers between 0 and 15. The transmission time therefore depends on the transmitted data values. The single edge is defined by a 3 Unit Time (UT, see Chapter 5.4.1) low pulse on the output, followed by the high time defined in the protocol (nominal values, may vary depending on the tolerance of the internal oscillator and the influence of external circuitry). All values are multiples of a unit time frame concept. A transfer consists of the following parts (Figure 5-13):

- A trigger pulse by the master, which initiates the data transmission
- A synchronization period of 56 UT (in parallel, a new sample is calculated)
- A status nibble of 12-27 UT
- Between 3 and 6 data nibbles of 12-27 UT
- A CRC nibble of 12-27 UT
- An end pulse to terminate the SPC transmission


Figure 5-13 SPC frame example
The CRC checksum includes the status nibble and the data nibbles. It can be used to check the validity of the decoded data. The sensor is available for the next trigger pulse $90 \mu$ s after the falling edge of the end pulse (see Figure 5-14).


Figure 5-14 SPC pause timing diagram
In SPC mode, the sensor does not continuously calculate an angle from the raw data. Instead, the angle calculation starts after the recognized trigger nibble from the master in order to minimize timing jitter. In this mode, the AVAL register, which stores the angle value and can be read via SSC, contains the angle which was calculated after the last SPC trigger nibble.This means that in any case, to update the registers and read the data via SSC, a trigger nibble has to be previously generated.


Figure 5-15 SPC configuration in open drain mode
In parallel to SPC, the SSC interface can be used for individual configuration. The number of transmitted SPC nibbles can be changed to customize the amount of information sent by the sensor. The frame contains a 16-bit angle value and an 8-bit temperature value in the full configuration (Table 5-8).
Sensors with preset SPC are available as TLE5012B E9000. The register settings for these sensors can be found in the Chapter 7.

Table 5-8 Frame configuration

| Frame type | IFAB_RES | Data nibbles |
| :--- | :--- | :--- |
| 12-bit angle | 00 | 3 nibbles |
| 16-bit angle | 01 | 4 nibbles |
| 12-bit angle, 8-bit temperature | 10 | 5 nibbles |
| $16-$ bit angle, 8-bit temperature | 11 | 6 nibbles |

The status nibble, which is sent with each SPC data frame, provides an error indication similar to the Safety Word of the SSC protocol. In case the sensor detects an error, the corresponding error bit in the Status register is set and either the bit SYS_ERR or the bit ELEC_ERR of the status nibble will be "high", depending on the kind of error (see Table 5-9). As long as a fault is present, the error information will be transmitted in SPC frames. Any fault will be communicated at least once by the SPC frame (even if the fault happened and disappeared before the trigger nibble).

Table 5-9 Structure of status nibble

| Name | Bits | Description |
| :--- | :--- | :--- |
| SYS_ERR | $[3]$ | Indication of system error (S_FUSE, S_OV, S_XYOL, S_MAGOL, S_ADCT) <br> 0: No system error <br> 1: System error occurred |
| ELEC_ERR | $[2]$ | Indication of electrical error (S_RST, S_VR) <br> 0: No electrical error <br> 1: Electrical error occurred <br> Both hardware and software resets will set this bit at "1" for the first status <br> nibble after the reset (S_RST). |
| S_NR | $[1]$ | Slave number bit 1 (level on IFC) |
|  | $[0]$ | Slave number bit 0 (level on SCK) |

### 5.4.1 Unit Time Setup

The basic SPC protocol unit time granularity is defined as $3 \mu \mathrm{~s}$. Every timing is a multiple of this basic time unit.To achieve more flexibility, trimming of the unit time can be done within IFAB_HYST. This enables a setup of different unit times.

Table 5-10 Predivider setting

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Typ. | Max. |  |  |
| Unit time | $t_{\text {Unit }}$ |  | 3.0 |  | $\mu \mathrm{s}$ | IFAB_HYST $=00{ }^{1)}$ |
|  |  |  | 2.5 |  |  | IFAB_HYST $=01^{1)}$ |
|  |  |  | 2.0 |  |  | IFAB_HYST $=10^{1)}$ |
|  |  |  | 1.5 |  |  | IFAB_HYST $=11^{1)}$ |

[^1]
### 5.4.2 Master Trigger Pulse Requirements

An SPC transmission is initiated by a master trigger pulse on the IFA pin. To detect a low-level on the IFA pin, the voltage must be below a threshold $\mathrm{V}_{\mathrm{th}}$. The sensor detects that the IFA line has been released as soon as $\mathrm{V}_{\text {th }}$ is crossed. Figure 5-16 shows the timing definitions for the master pulse. The master low time $\mathrm{t}_{\text {mlow }}$ as well as the total trigger time $\mathrm{t}_{\mathrm{mtr}}$ are given in Table 5-11.
If the master low time exceeds the maximum low time, the sensor does not respond and is available for a next triggering $30 \mu \mathrm{~s}$ after the master pulse crosses $\mathrm{V}_{\text {thr }} . \mathrm{t}_{\text {md,tot }}$ is the delay between internal triggering of the falling edge in the sensor and the triggering of the ECU.


Figure 5-16 SPC Master pulse timing

Table 5-11 Master pulse parameters

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min. | Typ. | Max. |  |  |
| Threshold | $V_{\text {th }}$ |  | 50 |  | $\begin{aligned} & \% \text { of } \\ & V_{D D} \end{aligned}$ | 1) |
| Threshold hysteresis | $V_{\text {thhyst }}$ |  | 8 |  | $\begin{aligned} & \% \text { of } \\ & V_{D D} \end{aligned}$ | $V_{D D}=5 \mathrm{~V}^{1)}$ |
|  |  |  | 3 |  |  | $\mathrm{V}_{\mathrm{DD}}=3 \mathrm{~V}^{1}$ |
| Total trigger time | $t_{\text {mtr }}$ |  | 90 |  | UT | SPC_Trigger $=0 ;{ }^{1 / 2)}$ |
|  |  |  | $\begin{aligned} & \mathrm{t}_{\text {mlow }} \\ & +12 \end{aligned}$ |  | UT | SPC_Trigger $=1^{1)}$ |
| Master low time | $t_{\text {mlow }}$ | 8 | 12 | 14 | UT | S_NR $=00^{1}$ |
|  |  | 16 | 22 | 27 |  | S_NR $=01^{1)}$ |
|  |  | 29 | 39 | 48 |  | S_NR = $10^{1}$ ) |
|  |  | 50 | 66 | 81 |  | S_NR = 11 ${ }^{1)}$ |
| Master delay time | $t_{\text {md,tot }}$ |  | 5.8 |  | $\mu \mathrm{s}$ | 1) |

1) Not subject to production test - verified by design/characterization
2) Trigger time in the sensor is fixed to the number of units specified in the "typ." column, but the effective trigger time varies due to the sensor's clock variation

## Total trigger time

The SPC_Trigger is set to 0 by default. For a variable-length SPC Trigger Nibble -and therefore an overall shorter SPC Frame- the SPC_Trigger bit can be set to 1 via the SSC interface. The SPC_Trigger bit is the second MSB of the HSM_PLP bits of the MOD_4 register (address $0 \mathrm{E}_{\mathrm{H}}$ ). Check Chapter 6.2 for further details.

### 5.4.3 Checksum Nibble Details

The checksum nibble is a 4-bit CRC of the data nibbles including the status nibble. The CRC is calculated using the polynomial $x^{4}+x^{3}+x^{2}+1$ with a seed value of 0101. The remainder after the last data nibble is used are transferred as CRC.

## CRC calculation example with SPC interface:

The following example shows the CRC generation for a typical SPC frame with three data nibbles (default setting). The status nibble is $0000_{\mathrm{B}}$ as there are no errors and the slave number is the $00_{\mathrm{B}}$ (IFC and SCK pin connected to ground as shown in the application circuits chapter). The following three data nibbles provide the angle value.
At the beginning the CRC is set at $0000_{\mathrm{B}}$ (see Figure 5-18, line 1). The first step to generate the CRC consists in a XOR logical operation (line 3) between the status nibble (line 1) and the seed value $0101_{\mathrm{B}}$ (line 2). Align the generator polynomial (line 4) to the non-zero MSB of the dataset out of the first step (line 3) and calculate another XOR (line 5).


Figure 5-17 TLE5012B's CRC generator polynomial for the SPC interface
From this point onwards, reiterative XOR logical operations between the data (result of the previous operation) and the generator polynomial are done till the remaining bits are equal or smaller than $0 \times 0 F_{H}$ (only 4 bits left).


Figure 5-18 CRC generation example with SPC interface

## CRC generation software code example

```
//"message" is the data transfer for which a CRC has to be calculated.
//A typical "message" consists of the status nibble, three data nibbles and the CRC
//nibble (the trigger nibble and the synchronisation nibble are not part of the CRC).
//"Length" is the number of nibbles in the "message". A typical "message" has 5
//nibbles (the trigger nible and the synchronization nibble are not part of the CRC).
unsigned char CRC(unsigned char *message, unsigned char Length)
{
//"crc" defined as the 4-bits that will be generated through the message till the
//final "crc" is generated. In the example above this are the blue lines out of the
//XOR operation.
    unsigned char crc;
//"Numnibbles" is a counter to compare the bits used for the CRC calculation and
//"Length".
    unsigned char Numnibbles, bitdata;
//Initially the CRC remainder has to be set with the original seed (0x05 for the
/ /TLE5012B).
    crc = 0x05;
//For all the nibbles of the message.
    for(Numnibbles=0; Numnibbles<Length; Numnibbles++)
    {
//"crc" is calculated as the XOR operation from the previous "crc" and the "message".
//"^" is the XOR operator.
    crc ^= message[Numnibbles];
//For each bit position in a 4-bit nibble
    for(bitdata=0; bitdata<4; bitdata++)
    {
//If the MSB of the "crc" is 1 (with the &0x80 mask we get the MSB of the crc).
        if((crc&0x08)!=0)
        {
//"crc" advances on position ("crc" is moved left 1 bit: the MSB is deleted since it
//will be cancelled out with the first one of the generator polynomial and a new bit
//from the "message" is taken as LSB.)
        crc <<=1;
//"crc" is calculated as the XOR operation from the previous "crc" and the generator
//polynomial (0x0D for TLE5012B). Be aware that here the x4 bit is not taken since
//the MSB of the "crc" already has been deleted in the previous step.
        crc ^= 0x0D;
        }
//In case the "crc" MSB is 0
        else
//"crc" advances one position (this step is to ensure that the XOR operation is only
//done when the generator polynomial is aligned with a MSB of the message that is " 1".
                crc <<= 1;
        }
    }
```

```
//Return the "crc" remainder. The &0x0F mask is a safety check to ensure four LSBs
//only and rest 0's.
    return(crc&0x0F);
}
```


## Disclaimer

The CRC generation software code provided above shall be used as guidance to the developer of solutions with the TLE5012B. Infineon is not responsible for malfunctioning of the code provided above. This code was used with an Infineon's microcontroller XC878.

- The CRC generation software code is only provided as a hint for the implementation or the use of the Infineon Technologies components and shall not be regarded as any description or warrant of a certain functionalities, conditions or quality of the Infineon Technologies component(s).
- All statements contained in this code, including recommendation or suggestion or methodology, are to be verified by the user before implementation or use, as operating conditions and environmental factors may differ. The recipient of this code must verify any function described herein in the real application.
- Infineon Technologies hereby disclaims any and all warranties and liabilities of any kint (including without limitation warranties of non-infringement of intellectual property rights of any third party) with respect to any and all code given in this document.


### 5.5 Hall Switch Mode (HSM)

The Hall Switch Mode (HSM) within the TLE5012B makes it possible to emulate the output of 3 Hall switches. Hall switches are often used in electrical commutated motors to determine the rotor position. With these 3 output signals, the motor will be commutated in the right way. Depending on which pole pairs of the rotor are used, various electrical periods have to be controlled. This is selectable within $0 \mathrm{E}_{\mathrm{H}}$ (HSM_PLP). Figure 5-19 depicts the three output signals with the relationship between electrical angle and mechanical angle. The mechanical $0^{\circ}$ point is always used as reference.
The HSM is generally used with push-pull output, but it can be changed to open-drain within the register IFAB_OD. Sensors with preset HSM are available as TLE5012B E3xxx. The register settings for these sensors can be found in the Chapter 6.2.


Figure 5-19 Hall Switch Mode
The HSM Interface can be selected via SSC (IF_MD = 010).

Table 5-12 Hall Switch Mode

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :--- | :--- | :--- | :---: | :---: | :---: | :--- |
|  |  |  | Min. | Typ. | Max. |  |

Table 5－12 Hall Switch Mode（cont＇d）

| Parameter | Symbol | Values |  |  | Unit | Note／Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min． | Typ． | Max． |  |  |
| Electrical angle accuracy | $\alpha_{\text {elect }}$ |  | 0.6 | 1 | 。 | 1 pole pair with autocalibration ${ }^{12)}$ |
|  |  |  | 1.2 | 2 | 。 | 2 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 1.8 | 3 | － | 3 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 2.4 | 4 | － | 4 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 3.0 | 5 | － | 5 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 3.6 | 6 | － | 6 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 4.2 | 7 | － | 7 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 4.8 | 8 | － | 8 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 5.4 | 9 | － | 9 pole pairs with autocal．${ }^{1 / 2)}$ |
|  |  |  | 6.0 | 10 | 。 | 10 pole pairs with autocal．${ }^{12)}$ |
|  |  |  | 6.6 | 11 | 。 | 11 pole pairs with autocal．${ }^{122)}$ |
|  |  |  | 7.2 | 12 | － | 12 pole pairs with autocal．${ }^{12)}{ }^{2}$ |
|  |  |  | 7.8 | 13 | － | 13 pole pairs with autocal．${ }^{122)}$ |
|  |  |  | 8.4 | 14 | 。 | 14 pole pairs with autocal．${ }^{12)}$ |
|  |  |  | 9.0 | 15 | － | 15 pole pairs with autocal．${ }^{12)}$ |
|  |  |  | 9.6 | 16 | － | 16 pole pairs with autocal．${ }^{12)}$ |
| Mechanical angle switching hysteresis | $\mathrm{a}_{\text {HShystm }}$ | 0 |  | 0.703 | － | Selectable by IFAB＿HYST ${ }^{2 / 334)}$ |

Table 5－12 Hall Switch Mode（cont＇d）

| Parameter | Symbol | Values |  |  | Unit | Note／Test Condition |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min． | Typ． | Max． |  |  |
| Electrical angle switching hysteresis ${ }^{5)}$ | $\alpha_{\text {HShystel }}$ |  | 0.70 |  | 。 | 1 pole pair； $\text { IFAB_HYST }=11^{1) 2}$ |
|  |  |  | 1.41 |  | － | 2 pole pairs； IFAB_HYST=111)2) |
|  |  |  | 2.11 |  | 。 | 3 pole pairs； $\text { IFAB_HYST=11 }{ }^{112)}$ |
|  |  |  | 2.81 |  | 。 | 4 pole pairs； IFAB_HYST=11112) |
|  |  |  | 3.52 |  | 。 | 5 pole pairs； $\text { IFAB_HYST=11 }{ }^{1) 2}$ |
|  |  |  | 4.22 |  | 。 | 6 pole pairs； $\text { IFAB_HYST=11 }{ }^{1) 2}$ |
|  |  |  | 4.92 |  | － | 7 pole pairs； IFAB_HYST=11112) |
|  |  |  | 5.62 |  | － | 8 pole pairs； $\text { IFAB_HYST=11 }{ }^{112)}$ |
|  |  |  | 6.33 |  | － | 9 pole pairs； IFAB_HYST=111)2) |
|  |  |  | 7.03 |  | － | 10 pole pairs； IFAB＿HYST＝11 ${ }^{1{ }^{12)}}$ |
|  |  |  | 7.73 |  | － | 11 pole pairs； IFAB＿HYST＝11 ${ }^{1{ }^{12}}$ |
|  |  |  | 8.44 |  | － | 12 pole pairs； IFAB＿HYST＝11 ${ }^{1 \text { 12）}}$ |
|  |  |  | 9.14 |  | 。 | 13 pole pairs； IFAB＿HYST＝11 ${ }^{1 \text { 12）}}$ |
|  |  |  | 9.84 |  | － | 14 pole pairs； IFAB＿HYST＝11 ${ }^{\left.1{ }^{12}\right)}$ |
|  |  |  | 10.55 |  | － | 15 pole pairs； IFAB＿HYST＝11 ${ }^{1 \text { 12）}}$ |
|  |  |  | 11.25 |  | － | 16 pole pairs； IFAB＿HYST＝11 ${ }^{1 \text { 12）}}$ |
| Fall time | $\mathrm{t}_{\text {HSfall }}$ |  | 0.02 | 1 | $\mu \mathrm{S}$ | $\left.\mathrm{R}_{\mathrm{L}}=2.2 \mathrm{k} \Omega ; \mathrm{C}_{\mathrm{L}}<50 \mathrm{pF}{ }^{2}\right)$ |
| Rise time | $\mathrm{t}_{\text {HSrise }}$ |  | 0.4 | 1 | $\mu \mathrm{S}$ | $\mathrm{R}_{\mathrm{L}}=2.2 \mathrm{k} \Omega ; \mathrm{C}_{\mathrm{L}}<50 \mathrm{pF}{ }^{2}$ |

1）Depends on internal oscillator frequency variation（see Data Sheet）
2）Not subject to production test－verified by design／characterization
3）GMR hysteresis not considered
4）Minimum hysteresis without switching
5）The hysteresis has to be considered only at change of rotation direction

To avoid switching due to mechanical vibrations of the rotor，an artificial hysteresis is recommended（Figure 5－20）．

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Figure 5-20 HS hysteresis

### 5.6 Incremental Interface (IIF)

The Incremental Interface (IIF) emulates the operation of an optical quadrature encoder with a 50\% duty cycle. It transmits a square pulse per angle step, where the width of the steps can be configured from 9bit ( 512 steps per full rotation) to 12 bit ( 4096 steps per full rotation) within the register MOD_4 (IFAB_RES) ${ }^{1}$. The rotation direction is given either by the phase shift between the two channels IFA and IFB (A/B mode) or by the level of the IFB channel (Step/Direction mode), as shown in Figure 5-21 and Figure 5-22. The incremental interface can be configured for A/B mode or Step/Direction mode in register MOD_1 (IIF_MOD).
Using the Incremental Interface requires an up/down counter on the microcontroller, which counts the pulses and thus keeps track of the absolute position. The counter can be synchronized periodically by using the SSC interface in parallel. The angle value (AVAL register) read out by the SSC interface can be compared to the stored counter value. In case of a non-synchronization, the microcontroller adds the difference to the actual counter value to synchronize the TLE5012B with the microcontroller.

After startup, the IIF transmits a number of pulses which correspond to the actual absolute angle value. Thus, the microcontroller gets the information about the absolute position. The Index Signal that indicates the zero crossing is available on the IFC pin.
Sensors with preset IIF are available as TLE5012B E1000. The register settings for these sensors can be found in Chapter 6.2.

## A/B Mode

The phase shift between Phase $A$ and Phase $B$ is determined by the rotation direction of the magnet. By default (ANG_DIR = 0), Phases A follows Phase B to indicate clockwise rotation direction, while Phase B follows Phase A to indicate counterclockwise rotation direction. This behaviour is inverted by setting ANG_DIR $=1$.


Figure 5-21 Incremental interface with A/B mode

## Step/Direction Mode

Phase A pulses out the increments and phase B indicates the direction.


Figure 5-22 Incremental interface with Step/Direction mode

1) Decreasing the number of bits does not increase the maximum rotation speed.

## Startup pulses

Just after startup, in absolute mode (default mode in the register MOD_4, bits HSM_PLP), the IIF generates the number of pulses needed to count to the initial angle position on the shortest direction. These pulses may be generated at the maximum frequency on both IFA and IFB pin (see Table 5-13) and therefore the start up pulses may take up to 2.1 ms to count to an initial angle position of $180^{\circ}$ (maximum angular distance). The counting direction may change once the startup position has been reached (depending on whether the shortest direction matched the actual rotation direction or not). Changes of angle position from the initial position during the start-up pulses are tracked.


Figure 5-23 Increcremental Interface startup pulses and first step movements at different speeds
The number of pulses indicates the angle value position. The angle can be calculated counting the numjber of pulses:

$$
\begin{equation*}
\text { angle }=\frac{\# \text { pulses } * 360^{\circ}}{2^{12}} \tag{5.9}
\end{equation*}
$$

Or measuring the length (in seconds) of the train of pulses:

$$
\begin{equation*}
\text { angle }=\frac{\text { length }(\mathrm{sec})^{* 360^{\circ}}}{2^{12} * 10^{-6}} \tag{5.10}
\end{equation*}
$$

The actual increment needed to reach a new angle position is updated every update rate time ( $\mathrm{t}_{\text {upd }}$ ). Depending on the angle speed, pulses are distributed evenly over the update rate time ( $\mathrm{t}_{\text {upd }}$ ) up to the maximum increment frequency specified in Table 5-13.
Figure 5-24 shows an example where the last pulses have a different frequency. If 1000 pulses ( $\sim 87.9^{\circ}$ angle at startup) have to be transmitted at startup, $1000 \mu \mathrm{~s}$ are needed (at maximum frequency). With the default angle update rate time ( $\mathrm{t}_{\text {upd }}=42.7 \mu \mathrm{~s}$ ), $23.44 \mathrm{t}_{\text {upd }}(1000$ pulses * $1 \mathrm{MHz} / 42.7 \mu \mathrm{~s}$ ) are required to transmit the 1000 pulses. In reality $24 \mathrm{t}_{\text {upd }}$ are used. The first $23 \mathrm{t}_{\text {upd }}$ send 982 pulses at $1 \mathrm{MHz}\left(23 \mathrm{t}_{\text {upd }}{ }^{*} 42.7 \mu \mathrm{~s}^{*} 1 \mathrm{Mhz}\right)$. The remainig 18 pulses are not send at $1 \mathrm{MHz}\left(0.44 \mathrm{t}_{\text {upd }}\right)$ but at a frequency so that the 18 remaining pulses are distributed over the whole $\mathrm{t}_{\text {upd }}$ (that is a frequency of 422 kHz ).


Figure 5-24 Increcremental Interface startup pulses frequency

## IIF Index

The IFC pin -or IIF Index- generates one pulse at zero crossing. This output can be used as check or as comparison with the Phase A/Phase B outputs. The IIF Index pulse will be generated when the internal Incremental Interface Counter steps over $0^{\circ}$. The IIF Index pulse width ( $\mathrm{t}_{0^{\circ}}$ ) duration is specified in Table 5-13.


Figure 5-25 IIF Index pulse in A/B Mode


Figure 5-26 IIF Index pulse in Step/Direction Mode
Note: In Figure 5-25 and Figure 5-26 the Index pulse timing shows the start time of the Index pulse. In applications rotating above 2930rpm the period of Phase $A / B$ will be smaller than the length of the Index pulse.

## Hysteresis effect when changing rotation direction

The TLE5012B has an hysteresis threshold to avoid pulsing unintended steps due to mechanical vibrations of the rotor or system. The default hysteresis is $0.703^{\circ}$ and it can be changed in the register IFAB (IFAB_HYST). Once the hysteresis threshold is surpassed, the Phase A and Phase B output the missed steps and continue to work in their normal operation mode. Pulsing the missed pulses allows to count all the steps and correctly calculate the angle position. The number of missed pulses depends on the hysteresis threshold and on the step resolution.


Figure 5-27 Phase A/B output during a rotation direction change due to the hysteresis threshold

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## Table 5-13 Incremental Interface

| Parameter | Symbol | Values |  |  | Unit | Note / Test Condition |
| :--- | :--- | :--- | :--- | ---: | :--- | :--- |
|  |  | Min. | Typ. | Max. |  |  |
| Incremental output frequency | $\mathrm{f}_{\text {Inc }}$ |  |  | 1.0 | MHz | Frequency of phase A and <br> phase $\mathrm{B}^{1)}$ |
| Index pulse width | $\mathrm{t}_{0^{\circ}}$ |  | 5 |  | $\mu \mathrm{~s}$ | $0^{\circ 1)}$ |

1) Not subject to production test - verified by design/characterization

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SSC Registers

## 6 SSC Registers

The TLE5012B includes several registers that can be accessed via Synchronous Serial Communication (SSC) to read data as well as to write to configure settings.

### 6.1 Registers Overview

There are twenty-two documented registers, but only a few are relevant to read data or to configure the TLE5012B. Many extra features that are also documented may only be used in very specific cases. In the following bitmap the relevant bits can be identified.

The most important bits are the ones indicated in green, orange and grey. The green bits contain calculated data; the bright green bits are additional data that may only be relevant for some specific applications. The orange bits are configuration parameters, which can be changed if the default values are not the desired ones. The dark orange bits are relevant if connecting several devices (sensors) to a same master (microcontroller). The grey bits are relevant for diagnosis to address the demands for functional safety.
There are also yellow bits for the autocalibration and calibration values. Finally the purple bits mark extra features that can be configured, if desired.


Figure 6-1 Bitmap Part 1

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SSC Registers


Figure 6-2 Bitmap Part 2


| $\square$ | Other Configuration |
| :--- | :--- |
| $\square$ | Diagnosis |
| Reserved bits |  |

Figure 6-3 Colour legend for the Bitmap

## Most relevant data and configuration bits

The most relevant data and configuration bits are described below. To find more details (e.g. whether to set the bit to "high" or "low"), please refer to Chapter 6.2.

Angle value: the angle value can be found in the AVAL register $\left(02_{H}\right)$ under the ANG_VAL bits (bits 14:0).

Angle speed: the angle speed can be found in the ASPD register $\left(03_{H}\right)$ under the ANG_SPD bits (bits 14:0).

Number of revolutions: the number of revolutions can be found in the AREV register $\left(04_{H}\right)$ represented by the REVOL bits (bits 8:0). For every full rotation in counter-clockwise direction the number of revolutions increments by one; for every full rotation in clockwise direction it decrements by one.

Raw values from the two GMR sensors: the raw values from the two GMR sensors can be accessed via the ADC_X and ADC_Y registers ( $10_{\mathrm{H}}$ and $11_{\mathrm{H}}$ respectively).

Resolution: the MOD_4 register $\left(0 E_{H}\right)$ contains two IFAB_RES bits (bits $4: 3$ ) that are multi-purpose. For each interface these bits allow to choose between four different resolutions if the default ones are not the most adequate for the application. For PWM interface the frequency can be chosen from 244 Hz to 1953 Hz , therefore it can be chosen how often the updated angle value has to be transmitted. For IIF pulses can be transmitted for different step resolutions from $0.088^{\circ}$ to $0.703^{\circ}$. For SPC it can be chosen if angle resolution should be in 12 or 16 bits, or also if two extra nibbles for the temperature should be transmitted. At reset the default resolution is restored.

Interface mode: there are different TLE5012B derivates with different default interfaces. Still, the interface of the TLE5012B can also be chosen via SSC at start-up by setting the two IF_MD bits (bits 1:0) of the MOD_4 register $\left(0 \mathrm{E}_{\mathrm{H}}\right)$. At reset the default interface of the derivate is restored. It is recommended to configure any IF_MD setting early after a hardware reset to guarantee a correct switch to the desired interface mode.

Autocalibration: the TLE5012B is a factory-calibrated sensor. Still, automatic calibration of offset and amplitude synchronicity can be enabled for applications with full-turn capability in the MOD_2 register ( $08_{H}$ ) under the AUTOCAL bits (bits 1:0) to compensate lifetime and temperature effects. At reset the default factory-calibrated parameters are restored. For further information on autocalibration refer to Chapter 4.1.

Prediction: the prediction function can be enabled/disabled in the MOD_2 register $\left(08_{H}\right)$ under the PREDICT bit (bit 2). As described in Chapter 4.2 Prediction allows to calculate the angle value around one period ( $\mathrm{t}_{\text {update }}$ ) before than if prediction is disabled. The prediction function is linear and may not be recommended for cases where the rotation speed changes abruptly. At reset the default status is restored.

### 6.1.1 Bit Types

The TLE5012B contains read, write and update registers as described in Table 6-1.

Table 6-1 Bit Types

| Abbreviation | Function | Description |
| :--- | :--- | :--- |
| r | Read | Read-only registers |
| w | Write | Read and write registers |
| u | Update | Update buffer for this bit is present. If an update is triggered, the immediate <br> values are stored in this update buffer simultaneously. This enables a <br> snapshot of all necessary system parameters at the same time. |

Write bits are mostly for configuration purposes. Mostly to select other configuration settings than the default ones from the derivate (e.g. change resolution, hysteresis, update rate, enable/disable features such as autocalibration...), but also possible to overwrite compensation parameters.
Some bits are also marked as update bits. This function is meant to obtain the data from multiple registers in the very exact moment. In normal operation, if a Command Word is sent to read multiple registers, due to the fact that some time is needed to process each READ, we will be reading registers in different moments (current data is read, not data from the same point in time).

To read data from the very exact time (and not current data) an Update-Event has to be generated before sending the command word. As explained in Chapter 5.2.2 under the Data communication via SSC section, the UpdateEvent is generated by setting the CSQ line to low for $1 \mu \mathrm{~s}\left(\mathrm{t}_{\mathrm{cSupdate}}\right)$. This will store the values in the update buffer at the same time; it is a snapshot. These values will remain in the buffer till another Update-Event is generated or till the TLE5012B is switched off.
To read the update buffer which has just been generated, the Command World has to set the UPD (UpdateRegister Access) bit to high. The Command Word structure is described in Chapter 5.2.2 under the SSC Data Transfer section. With UPD set to high the update buffer will be read, which contains the data from the very exact moment and not the normal registers (which contain current values).
,

### 6.1.2 Communication Examples

This chapter gives some short SSC communication examples. The sensor has to be selected first via CSQ, and SCK must be available for the communication.


Figure 6-4 SSC command to read angle value


Figure 6-5 SSC command to read angle speed and angle revolution


Figure 6-6 SSC command to change Interface Mode2 register

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## Writing process to avoid overwritting

When writing in a certain field of a register, it is important to not overwrite the bits from the other fields in the same register. Therefore -for the registers with many fields- a read has to be done previous to a write, so the content of the bits from the register can be written back and avoid unintended overwriting in other fields than the desired field. After a write is recommended to do a read to ensure that the values are correctly set. Figure 6-7 shows the described sequence when a configuration parameter needs to be changed.


Figure 6-7 SSC data transfer sequence to change a configuration parameter
In the following example the Incremental Interface resolution of a TLE5012B E1000 derivate will be changed from the default $0.088^{\circ}$ (IFAB_RES bits $00_{B}$ in the MOD_4 register) to $0.352^{\circ}$ (IFAB_RES bits $10_{B}$ ) via a SSC data tranfer. First, the whole MOD_4 register is read. The bits will be copied in the write word and only the two IFAB_RES bits changed to the desired configuration. Finally a read confirms that the desired bits have changed and the rest of the bits remain as they were.

| COMMAND |  |  |
| :---: | :---: | :---: |
| D0E1 ${ }_{\text {H }}$ |  |  |
| R LOCK | ADDR | ND |
| MSB |  | LSB |
| 11010 | 111 | 001 |

( $\mathrm{t}_{\text {wr_delay }}$ )


| COMMAND |  |  | WRITE Data 1 |  |  | $\left(\mathrm{t}_{\text {wr_delay }}\right)$ | SAFETY-WORD |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $50 \mathrm{E} 1_{\mathrm{H}}$ |  |  | $4830_{\text {H }}$ |  |  |  | $\mathrm{FE} 3_{\mathrm{H}}$ |  |  |  |  |
| W LOCK | ADDR | ND | TCO_X_T | HSM_PLPRES\| | MD |  | STAT | RESP |  | CRC |  |
| MSB | LSB |  | MSB | LSB |  |  | MSB |  | LSB |  |  |
| 01010 | 111 | 001 | 010010 | 000110 | 000 |  | 111 | 1110 | 11 | 00 | 011 |


| COMMAND |  |  | $\left(\mathrm{t}_{\mathrm{wr} \text { _delay }}\right)$ | READ Data 1 |  |  |  |  | SAFETY-WORD |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| D0E1 ${ }_{\text {H }}$ |  |  |  | $4830_{H}$ |  |  |  |  | FE40 ${ }_{\text {H }}$ |  |  |  |  |
| R LOCK | ADDR | ND |  |  | TCO_X_T | HSM_PLP |  | MD | STAT | RESP | CRC |  |  |
| MSB |  | LSB |  | MSB |  |  |  | LSB | MSB |  |  |  | LSB |
| 1101000011100001 |  |  |  | 010 | 0010 | 0001 | 10 | 000 | 111 | 1110 | 10 | 00 | 000 |

Figure 6-8 Example of a SSC data transfer sequence to change a configuration parameter

### 6.1.3 Signed registers and Two's complement

Many registers are described as signed registers. Data in the registers such as the Angle Speed and also configuration parameters such as the X and Y Offset, the Amplitude Synchronicity, Orthogonality Correction and the Offset Temperature Coefficients are, among others, signed registers. That means, that they are stored in two's complement. The Angle Value is also a signed register ( $-180^{\circ} \ldots 179.9^{\circ}$ ), but can also be viewed as unsigned (0...359.9 ${ }^{\circ}$ ).

A two's complement number is generated by the following equation:

$$
\begin{equation*}
\text { Value }=-b_{M S B} * 2^{N-1}+\sum_{i=0}^{N-2} b_{i} * 2^{i} \tag{6.1}
\end{equation*}
$$

For example, if the AVAL Register value is 1100110110010011 the MSB indicates that the RD_AV field is "high" and a new angle value is present (ANG_VAL). ANG_VAL are represented by the following 15 bits (100 11011001 0011). Therefore the angle value is:

$$
\begin{align*}
& \text { Value }=-b_{M S B} * 2^{N-1}+\sum_{i=0}^{N-2} b_{i} * 2^{i}=-1 * 2^{15-1}+0 * 2^{15-2}+0^{*} 2^{15-3}+1^{*} 2^{15-4}+1^{*} 2^{15-5}+0 * 2^{15-6}+1 * 2^{15-7}+  \tag{6.2}\\
& +1 * 2^{15-8}+0 * 2^{15-9}+0 * 2^{15-10}+1 * 2^{15-11}+0 * 2^{15-12}+0 * 2^{15-13}+1 * 2^{15-14}+1 * 2^{15-15}=-1 * 2^{14}+1 * 2^{11}+ \\
& +1^{*} 2^{10}+1 * 2^{8}+1 * 2^{7}+1 * 2^{4}+1 * 2^{1}+1 * 2^{0}=-16384+2048+1024+256+128+16+2+1=-12909
\end{align*}
$$

And if we calculate the angle (formula provided in the AVAL register description) we can calculate the angle:

$$
\begin{equation*}
\text { Angle }\left[^{\circ}\right]=\frac{360^{\circ}}{2^{15}} A N G_{-} V A L[\text { digits }]=\frac{360^{\circ}}{32768} *(-12909)=-141.82^{\circ} \tag{6.3}
\end{equation*}
$$

### 6.1.4 Zero position configuration

Each device has a factory-calibrated angle base to make the $0^{\circ}$ direction parallel to the edge of the chip.
For some applications it may be necessary to specifically set the $0^{\circ}$ angle position after sensor and magnet are assembled. In particular if interfaces are used which do not output the absolute angle, incremental interface or Hall-Switch-Mode, a mechanical reference position is to be defined in an end-of-line calibration.

Therefore, the following steps should be performed:

1. Move the mechanical assembly to the desired $0^{\circ}$-position.
2. Read the content of the ANG_BASE in the MOD_3 register (address $09_{\mathrm{H}}$ ).
3. Read the content of the AVAL register (address $02_{H}$ ) and remove the three LSBs to obtain a 12 bit angle value (rounded to minimize truncation error. To round, add $0 \times 0008$ to the read angle value prior to cut off the 3 LSBs).
4. Subtract (when ANG_DIR $=0$ ) or add (when ANG_DIR $=1$ ) the 12 bit angle value obtained in step 3 from the value of the ANG_BASE register and store the result in the non-volatile memory of the microcontroller.
5. On every start-up of the TLE5012B, write the stored value into the ANG_BASE register. The ANG_BASE register should be written before Autocalibration is enabled (so either disable Autocalibration to write this register, or write this register within the first $120 \mu$ s after a hardware reset).


Figure 6-9 Flow-Chart of ANG_BASE calibration procedure

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Figure 6-10 shows an example with the register values when setting the angle $191.9^{\circ}$ (or $-168.1^{\circ}$ ) as the $0^{\circ}$ position when ANG_DIR $=0$,

Turn mechanical assembly to desired $0^{\circ}$-position




| COMMAND |  |  | $\text { ( } \mathrm{t}_{\text {wr_delay }} \text { ) }$ | READ Data 1 |  |  |  | SAFETY-WORD |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| D091 ${ }_{\text {H }}$ |  |  |  | $7600_{\mathrm{H}}$ |  |  |  | $\mathrm{FE} 5 \mathrm{~B}_{\mathrm{H}}$ |  |  |  |  |
| R LOCK | ADDR | ND |  |  | , ${ }_{\text {_BASE }}$ |  |  | STAT | RESP |  | CRC |  |
| MSB |  | LS |  | MSB |  |  | LSB | MSB |  |  |  | LSB |
| 11010 | 0100 | 00 |  | 011 | 110 | 000 | 000 | 111 | 1110 | 1 | , | 011 |

Figure 6-10 SSC data transfer to configure the zero position
Figure 6-11 shows in other than the binary domain the values of the registers and the offset for the example above:

|  |  |  | Binary |  |  |  |  |  |  |  |  |  |  |  |  |  | Decimal | Resolution |  | Angle |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MSB |  |  |  |  |  |  |  |  |  |  |  |  | LSB |  | Bits | - |  |  |  |
|  | ANG_BASE | Unsigned |  |  | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 0 | 0 | - 1 |  | 11 | 4071 | 12 | 0.088 | 357.8 |  |  |
|  |  | Signed |  |  | -2048 | 1024 | 512 | 256 | 128 | 64 | 32 | 0 | 0 | 04 | 4 | 21 | -25 | 12 | 0.088 | -2.2 |  |  |
|  | ANG_VAL | Unsigned | 1 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | - 1 | 1 | 1 | 0 | 0 | 0 | 17465 | 15 | 0.011 | 191.9 |  |  |
|  |  | Signed | -16384 | 0 | 0 | 1024 | 0 | 0 | 0 | 0 | 32 | 16 | 8 | 80 | 0 | 01 | -15303 | 15 | 0.011 | -168.1 |  |  |
|  | ANG_VAL (12 MSBs) | Unsigned |  |  | 1 | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 01 | 1 | $1 \begin{array}{ll}1 & 1\end{array}$ | 2183 | 12 | 0.088 | 191.9 |  |  |
|  |  | Signed |  |  | -2048 | 0 | 0 | 0 | 128 | 0 | 0 | 0 | 0 | 0 | 4 |  | -1913 | 12 | 0.088 | -168.1 |  |  |
|  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  | $\downarrow$ | $\downarrow$ |
|  | ANG_BASE |  |  |  | 1 | 1 | 1 | 1 | 1 | 1 | 1 | 0 | 0 | - 1 |  |  |  |  |  |  | -2.2 | 357.8 |
| - | ANG_VAL |  |  |  | 1 | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | -1 | 1 | $1 \quad 1$ |  |  |  |  | -168.1 | 191.9 |
|  | OFFSET |  |  |  | 0 | 1 | 1 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 0 | 0 |  |  |  | $\downarrow$ | 165.9 | 165.9 |
|  |  |  |  |  | 0 | 1024 | 512 | 256 | 0 | 64 | 32 | 0 | 0 | 0 | 0 | 0 | 1888 | 12 | 0.088 | 165.9 |  |  |

Figure 6-11 Zero position configuration in different domains

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### 6.2 Registers Descriptions

This section describes the registers of the TLE5012B and replaces the TLE5012B Register Setting document. It also defines the read/write access rights of the specific registers. Table 6-2 identifies the values with symbols. Access to the registers is accomplished via the SSC Interface.

Table 6-2 Register Overview

| Register Short Name | Register Long Name | Offset Address | Page Number |
| :--- | :--- | :--- | :--- |

Registers Descriptions, Register Descriptions

| STAT | STATus register | $00_{H}$ | 75 |
| :---: | :---: | :---: | :---: |
| ACSTAT | ACtivation STATus register | $01_{\mathrm{H}}$ | 79 |
| AVAL | Angle VALue register | $02_{\mathrm{H}}$ | 81 |
| ASPD | Angle SPeeD register | $03_{\mathrm{H}}$ | 82 |
| AREV | Angle REVolution register | $04_{\mathrm{H}}$ | 83 |
| FSYNC | Frame SYNChronization register | $05_{\mathrm{H}}$ | 84 |
| MOD_1 | Interface MODe1 register | $06_{\mathrm{H}}$ | 85 |
| SIL | SIL register | $07_{\mathrm{H}}$ | 86 |
| MOD_2 | Interface MODe2 register | $08_{\mathrm{H}}$ | 88 |
| MOD_3 | Interface MODe3 register | $09_{\mathrm{H}}$ | 90 |
| OFFX | OFFset X | $0 \mathrm{~A}_{\mathrm{H}}$ | 91 |
| OFFY | OFFset Y | $0 \mathrm{~B}_{\mathrm{H}}$ | 91 |
| SYNCH | SYNCHronicity | $0 \mathrm{C}_{\mathrm{H}}$ | 92 |
| IFAB | IFAB register | $0 \mathrm{D}_{\mathrm{H}}$ | 93 |
| MOD_4 | Interface MODe4 register | $0 \mathrm{E}_{\mathrm{H}}$ | 94 |
| TCO_Y | Temperature COefficient register | $0 \mathrm{~F}_{\mathrm{H}}$ | 97 |
| ADC_X | ADC X-raw value | $10_{\mathrm{H}}$ | 98 |
| ADC_Y | ADC Y-raw value | $11_{\mathrm{H}}$ | 98 |
| D_MAG | Angle vector MAGnitude | $14_{\mathrm{H}}$ | 98 |
| T_RAW | Temperature sensor RAW-value | $15_{\mathrm{H}}$ | 100 |
| IIF_CNT | IIF CouNTer value | $20_{\mathrm{H}}$ | 101 |
| T250 | Temperature $25^{\circ} \mathrm{C}$ Offset value | $30_{\mathrm{H}}$ | 101 |

The registers are addressed wordwise.

## Configuration Register Checksum

To monitor the integrity of the sensor configuration, the TLE5012B performs a cyclic redundancy check of the configuration registers in address range $08_{\mathrm{H}}$ to $0 \mathrm{~F}_{\mathrm{H}}$. The corresponding 8 bit CRC checksum is stored in register CRC_PAR (address $0 \mathrm{~F}_{\mathrm{H}}$ ). When changing one or more of these registers, a new checksum has to be calculated from registers $08_{\mathrm{H}}$ to $0 \mathrm{~F}_{\mathrm{H}}$ using the generator polynomial described in Chapter 5.2.4, and written to the CRC_PAR register. Otherwise, a CRC fail error (status bit S_FUSE = 1) will occur. The CRC check can be disabled by setting register AS_FUSE to 0 . The execution of the cyclic redundancy check is automatically deactivated if auto calibration is active, as auto calibration performs periodical adjustments of several configuration registers.

## Derivate-Specific Reset Values:

The reset values of certain registers (for example interface settings) are set by laser fuses which are specific for the employed derivate (Exxxx number) of the TLE5012B. In this case, the reset values in the register table are marked as "derivate-specific". A list of specific reset values for all derivates is given in Chapter 7.6.

## Factory-Calibrated Reset Values:

The reset values of calibration registers (for example offset calibration) are set by laser fuses which are written during the factory calibration of the sensor. These values are specific for each individual device. In this case, the reset values in the register table are marked as "device-specific". When modifying parts of these registers, the register content should be read first, then only the relevant bits should be changed and the content should be written back into the register in order to avoid unintended over-writing of the calibration values.

## Multi-Purpose Registers:

Some configuration registers have more than one assignment and change different settings depending on the selected interface for the IFA, IFB, IFC pins (selectable via the IF_MD register, address $0 \mathrm{E}_{H}$ ). These registers are marked as "multi-purpose", and their assignments are described separately for each relevant interface.

### 6.2.1 Register Descriptions

## Status Register



| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| RD_ST | 15 | ru | Read Status <br> $0_{B} \quad$ status values not changed since last readout. <br> $1_{B} \quad$ status values changed. The bit is cleared on a readout (valid for both: normal operation and update buffer). Note: If an update event (register snapshot) is done after a normal read, RD_ST will not be set to $1_{\mathrm{B}}$ in the following read (either update read or normal read) unless a new value is available. <br> Reset: $1_{B}$ |
| S_NR | 14:13 | w | Slave Number <br> Used to identify up to four sensors in a bus configuration. The levels on pin SCK and pin IFC can be used to change the default slave number for SPC interface. Pin SCK represents S_NR[13] and pin IFC the S_NR[14]. Reset: $00_{B}$ |
| NO_GMR_A | 12 | ru | No valid GMR Angle Value <br> Cyclic check of DSPU output. Flag will be set as long as error persists and is not reset by SSC read-out. <br> $0_{B} \quad$ valid GMR angle value on the interface. <br> $1_{B} \quad$ no valid GMR angle value on the interface (e.g test vectors). <br> Reset: $0_{B}$ |

SSC Registers

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| NO_GMR_XY | 11 | ru | No valid GMR XY Values <br> Cyclic check of ADC input. Flag will be set as long as <br> error persists and is not reset by SSC read-out. <br> $0_{B} \quad$valid GMR_XY values on the ADC input and thus <br> on filter output. <br> no valid GMR_XY values on the ADC input (e.g. <br> test vectors). <br> S_ROM |
|  | 10 |  |  |
| S_ADCT |  |  |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| S_OV | 5 | ru | Status Overflow ${ }^{1)}$ <br> Cyclic check of DSPU overflow. This bit is updated based on the current angle value and thus the recommendation is to read it in update mode, if a consistent read-out is desired. The bit is reset by a normal SSC read-out. <br> Deactivation via AS_OV. <br> $0_{B} \quad$ No DSPU overflow occurred <br> $1_{B} \quad$ DSPU overflow occurred <br> Reset: $0_{B}$ |
| S_DSPU | 4 | $r$ | Status Digital Signal Processing Unit ${ }^{1)}$ Check of DSPU, CORDIC and CAPCOM at startup. Activation in operation via AS_DSPU possible, but only recommended during application halt and the error will not show up, since BIST does not set the error flag (only clears it). Error will only show up, after a watchdog stop has been triggered and is not cleared with a SSC readout, but only with a chip reset. <br> $0_{B}$ DSPU self-test ok <br> $1_{B} \quad$ DSPU self-test not ok, or self test is running <br> Reset: $0_{B}$ |
| S_FUSE | 3 | $r$ | Status Fuse CRC ${ }^{1)}$ <br> Cyclic CRC check of configuration registers $08_{\mathrm{H}}$ to $0 \mathrm{~F}_{\mathrm{H}}$ and startup CRC check of configuration fuses. A CRC error will remain as long as it persists and has not been read-out over SSC. Deactivation via AS_FUSE. CRC check is automatically disabled if auto calibration is active. <br> Note: When changing the content of one or more configuration registers in address range $08_{H}$ to $0 F_{H}$, a new CRC has to be calculated and stored in register CRC_PAR (address $0 F_{H}$ ), otherwise CRC fail will occur. Also see Chapter 4.1 section "Enabling and Disabling Autocalibration" for how to avoid S_FUSE errors in conjuction with autocalibration. <br> $0_{B}$ CRC ok <br> $1_{B} \quad$ CRC fail <br> Reset: $0_{B}$ |
| S_VR | 2 | r | Status Voltage Regulator ${ }^{1)}$ <br> Permanent check of internal and external supply voltages. Error will be signalized as long as it persists and has not been read out. Deactivation via AS_VR. <br> $0_{B} \quad$ Voltages ok <br> $1_{B} \quad V_{D D}$ over voltage; $V_{D D}$-off; GND-off; or $V_{\text {OvG }} ; V_{\text {OVA }}$; <br> $V_{\text {ovD }}$ too high <br> Reset: $0_{B}$ |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| S_WD | 1 | r | Status Watchdog <br> Permanent check of watchdog. After watchdog-counter overflow, the DSPU stops. Deactivation via AS_WD <br> $0_{B} \quad$ normal operation <br> $1_{B} \quad$ watchdog counter expired (DSPU stop), AS_RST must be activated. Outputs deactivated, pull up/down active. <br> Reset: $0_{B}$ |
| S_RST | 0 | ru | Status Reset ${ }^{2)}$ <br> Indication that there has been a reset state. <br> $0_{B} \quad$ no reset since last readout. <br> $1_{B}$ indication of power-up, short power-break, firmware or active reset. Both normal register and update buffer will indicate " 1 " if no prior read-out has been done (and even if no update pulse has been sent out). <br> Reset: $1_{B}$ |

1) bit remains " 1 " after error occurred. Bit is cleared to " 0 " when status register is read via SSC command.
2) bit remains " 1 " after reset occurred. Bit is cleared to " 0 " when status register is read via SSC command.

Note: When an error occurs, the corresponding bit in the safety word remains "0" until the status register is read.

## Activation Status Register

| ACSTAT <br> Activation | us Registe | Offset$\mathbf{0 1}_{\mathrm{H}}$ |  |  |  |  | Reset Value $18 E_{\text {H }}$ <br> 8 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 15 |  |  |  | 11 | 10 | 9 |  |
| Reserved |  |  |  |  | AS_FRST | AS_ADCT | Reserved |
|  |  | wu wu |  |  |  |  |  |
| 7 | 6 |  |  |  |  |  | 0 |
| AS_VEG_MAG | AS_VEC_XY | AS_OV | AS_DSPU | AS_FUSE | AS_VR | AS_WD | AS_RST |
| wu | wu | wu | wu | wu | wu | wu | w |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| Res | 15:11 | res | Reserved <br> Reset: $00011_{\mathrm{B}}$ (during operation may change to $01011_{\mathrm{B}}$ ) |
| AS_FRST | 10 | wu | Activation of Firmware Reset <br> All configuration registers retain their contents. $0_{B} \quad$ default or after execution of firmware reset. Firmware also sets S_RST at this point. $1_{B} \quad$ activation of firmware reset. Reset: $0_{B}$ |
| AS_ADCT | 9 | wu | Enable ADC Test vector Check <br> Activation of this test is only allowed with deactivated AUTOCAL. X, Y and Temp channel will be checked. $0_{B} \quad$ after execution. <br> $1_{B} \quad$ activation of ADC Test vector Check. <br> Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |
| AS_VEC_MAG | 7 | wu | Activation of Magnitude Check <br> $0_{B} \quad$ monitoring of magnitude disabled ${ }^{11}$. <br> $1_{B} \quad$ monitoring of magnitude enabled. <br> Reset: $1_{B}$ (for update buffer $\mathrm{O}_{\mathrm{B}}$ if no update command send before) |
| AS_VEC_XY | 6 | wu | Activation of $\mathrm{X}, \mathrm{Y}$ Out of Limit-Check <br> $0_{B} \quad$ monitoring of $X, Y$ Out of Limit disabled ${ }^{1)}$. <br> $1_{B} \quad$ monitoring of $X, Y$ Out of Limit enabled. <br> Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |
| AS_OV | 5 | wu | Enable of DSPU Overflow Check <br> $0_{B} \quad$ monitoring of DSPU Overflow disabled ${ }^{1)}$. <br> $1_{B} \quad$ monitoring of DSPU Overflow enabled. <br> Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| AS_DSPU | 4 | wu | Activation DSPU BIST <br> $0_{B} \quad$ after execution <br> $1_{B} \quad$ activation of DSPU BIST or BIST running <br> Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |
| AS_FUSE | 3 | wu | Activation Fuse CRC <br> A write in any of the fuse registers will set this bit automatically (automatically enabled by deactivation of AUTOCAL). AUTOCAL disables register CRC check regardless of the AS_FUSE setting. <br> $0_{B} \quad$ monitoring of CRC disabled. Clearing this <br> activation bit will also disable reporting of S_FUSE <br> errors after a remaining error has been read-out. <br> $1_{B} \quad$ monitoring of CRC enabled <br> Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |
| AS_VR | 2 | wu | Enable Voltage Regulator Check <br> $0_{B} \quad$ check of regulator voltages disabled. Clearing this activation bit will also disable reporting of S_VR error after a remaining error has been read-out. $1_{B} \quad$ check of regulator voltages enabled Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |
| AS_WD | 1 | wu | Enable DSPU Watchdog <br> $0_{B} \quad$ DSPU watchdog monitoring disabled. The S_WD status will be immediately cleared, when this bit is cleared. <br> $1_{B} \quad$ DSPU Watchdog monitoring enabled. <br> Reset: $1_{B}$ (for update buffer $0_{B}$ if no update command send before) |
| AS_RST | 0 | w | Activation of Hardware Reset <br> Activation occurs after CSQ switches from '0' to '1' after SSC transfer. <br> $0_{B} \quad$ after execution (write only, thus always returns " 0 "). $1_{B} \quad$ activation of HW Reset (S_RST is set). <br> Reset: $0_{B}$ |

[^2]
## Angle Value Register



## Angle Speed Register

| ASPD <br> Angle Speed Register |  | Offset 03 | Reset Value $8000_{\text {H }}$ |
| :---: | :---: | :---: | :---: |
| 15 | 14 |  | 8 |
| RD_AS |  | ANG_SPD |  |
| ru |  | ru |  |
| 7 |  |  | 0 |
|  |  | ANG_SPD |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| RD_AS | 15 | r | Read Status, Angle Speed <br> $0_{B} \quad$ no new angle speed value since last readout <br> $1_{B}$ new angle speed value (ANG_SPD) present. The bit is cleared on a read-out (valid for both: normal operation and update buffer). Note: If an update event (register snapshot) is done after a normal read, RD_AS will not be set to $1_{\mathrm{B}}$ in the following read (either update read or normal read) unless a new value is available. <br> Reset: $1_{B}$ |
| ANG_SPD | 14:0 | ru | Calculated Angle Speed <br> Signed value, where the sign bit [14] indicates the direction of the rotation. <br> Without prediction difference between the current unpredicted angle value and second-to-last unpredicted angle values. $\begin{equation*} \text { Speed }[\circ / s]=\frac{\frac{\text { AngleRange }\left[{ }^{\circ}\right]}{2^{15}} A N G \_S P D[\text { digits }]}{2 t_{u p d}[s]} \tag{6.5} \end{equation*}$ <br> With prediction, difference between the current predicted value and second-to-last unpredicted angle value. $\begin{equation*} \text { Speed }[\circ / s]=\frac{\frac{\text { AngleRange }\left[{ }^{\circ}\right]}{2^{15}} A N G-S P D[\text { digits }]}{3 t_{u p d}[s]} \tag{6.6} \end{equation*}$ <br> Reset: $0_{H}$ |

## Angle Revolution Register


ru

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| RD_REV | 15 | r | Read Status, Revolution <br> $0_{\mathrm{B}} \quad$no new values since last readout <br> $1_{\mathrm{B}}$ <br> new value (REVOL) present. The bit is cleared on <br> update buffer). Note: If an update event (register <br> snapshot) is done after a normal read, RD_REV will <br> not be set to $1_{\mathrm{B}}$ in the following read (either update <br> read or normal read) unless a new value is <br> available. <br> FCNT |
| $14: 9$ | wu | Reset: $1_{\mathrm{B}}$ |  |
| REVOL | Frame Counter (unsigned 6-bit value) <br> Internal frame counter. Increments every update period <br> (FIR_MD setting). <br> Reset: $0_{\mathrm{H}}$ |  |  |

## Frame Synchronization Register


ru

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| FSYNC | $15: 9$ | wu | Frame Synchronization Counter Value <br> Subcounter within one frame. Increments every internal <br> clock cycle (synchronously at a 750 kHz rate). Maximum <br> counter value depends on FIR_MD setting: 16 @ <br> FIR_MD=00; 32 @ FIR_MD=01; 64 @ FIR_MD=10; 128 <br> $@$ FIR_MD $=11$. |
| TEMPER |  | $8: 0$ | ru |

## Interface Mode1 Register

MOD_1
Interface Mode1 Register

Offset
$06_{\text {H }}$

Reset Value
derivate-specific

| 15 | 14 | 8 |  |
| :---: | :---: | :---: | :---: |
| FIR_MD |  | Res | 8 |

w

|  | 5 | 4 | 3 | 2 | 1 | 0 |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | Res |  | CLK_SEL | Res | DSPU_HO <br> LD | IIF_MOD |
|  | w |  | $w$ | $w$ |  |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| FIR_MD | 15:14 | w | Update Rate Setting (Filter Decimation) <br> $01_{\mathrm{B}} \quad 42.7 \mu \mathrm{~s}$ <br> $10_{\mathrm{B}} \quad 85.3 \mu \mathrm{~s}$ <br> 11B $\quad 170.6 \mu \mathrm{~s}$ <br> Reset: derivate-specific |
| CLK_SEL | 4 | w | Clock Source Select <br> Switch to external clock at start-up only. If there is no clock signal on the IFC pin when the chip is switched to the external clock source, the chip does not allow the switch (CLK_SEL remains zero, operation continued). If the external clock disappears with CLK_SEL already set, the chip will reset (PLL out of lock) and run on with the internal clock. <br> $0_{B} \quad$ internal oscillator <br> $1_{B} \quad$ external 4-MHz clock (IFC pin switched to input) <br> Reset: $0_{B}$ |
| DSPU_HOLD | 2 | w | Hold DSPU Operation ${ }^{1)}$ <br> If DSPU is on hold, no watchdog reset is performed by DSPU. Deactivate watchdog with AS_WD before setting DSPU on hold. <br> $0_{B} \quad$ DSPU in normal schedule operation $1_{B} \quad$ DSPU is on hold <br> Reset: $0_{B}$ |
| IIF_MOD | 1:0 | w | Incremental Interface Mode <br> $00_{B}$ IIF disabled <br> $01_{B} \quad A / B$ operation with Index on IFC pin <br> $10_{B}$ Step/Direction operation with Index on IFC pin <br> 11 $B$ not allowed <br> Reset: derivate-specific |

1) DSPU_HOLD is ignored in PWM or SPC mode.

## External Clock Selection:

External clock operation is possible for the interface configurations SSC only, SSC \& PWM, and SSC\& SPC. To switch the TLE5012B to external clock, the following procedure is used:

- Trigger a chip reset by writing a " 1 " to the AS_RST bit (address $01_{\mathrm{H}}[0]$ ) via SSC interface
- Within $120 \mu$ s after the reset command, write a " 1 " to the CLK_SEL bit (address $06_{\mathrm{H}}[4]$ )
- After the power-on time (max. 7 ms ), read the CLK_SEL bit via SSC interface to confirm that external clock is selected

Note: If the clock source (CLK_SEL) bit is switched to external clock during operation of the sensor without a reset it may occur, due to an internal timing conflict, that the switching command is not accepted and the chip keeps operating on internal clock.

## SIL Register



| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| FUSE_REL | 10 | w | Fuse Reload <br> Triggers reload of default values from laser fuses into configuration registers. <br> $0_{B} \quad$ normal operation <br> $1_{B} \quad$ reload of registers with fuse values immediately. Reloaded fuse values are used with the start of the next filter cycle. <br> Reset: $0_{B}$ |
| ADCTV_EN | 6 | w | ADC-Test Vectors <br> Diagnostic function to test ADCs. If enabled, sensor elements are internally disconnected and test voltages are connected to ADCs. NO_GMR_A and NO_GMR_XY status flags will be set to " 1 ", if this bit is set during operation. Test vectors can be selected via the register ADCTV_Y and ADCTV_X. <br> $0_{B} \quad$ ADC-Test Vectors disabled <br> $1_{B} \quad$ ADC-Test Vectors enabled <br> Reset: $0_{B}$ |
| ADCTV_Y | 5:3 | w | $\begin{aligned} & \text { Test vector } \mathrm{Y} \\ & 00 \mathrm{~B}_{\mathrm{B}} \quad 0 \mathrm{~V} \\ & 001_{\mathrm{B}}+70 \% \\ & 010_{\mathrm{B}}+100 \% \\ & 011_{\mathrm{B}}+\text { Overflow } \\ & 101_{\mathrm{B}}-70 \% \\ & 110_{\mathrm{B}}-100 \% \\ & 111_{\mathrm{B}}-\text { Overflow } \\ & \text { Reset: } 0_{\mathrm{H}} \\ & \hline \end{aligned}$ |
| ADCTV_X | 2:0 | w | $\begin{aligned} & \text { Test vector X } \\ & 000_{\mathrm{B}} \quad 0 \mathrm{~V} \\ & 001_{\mathrm{B}}+70 \% \\ & 010_{\mathrm{B}}+100 \% \\ & 011_{\mathrm{B}} \text { +Overflow } \\ & 101_{\mathrm{B}}-70 \% \\ & 110_{\mathrm{B}}-100 \% \\ & 111_{\mathrm{B}}-\text { Overflow } \\ & \text { Reset: } 0_{\mathrm{H}} \\ & \hline \end{aligned}$ |

## Interface Mode2 Register

MOD_2
Interface Mode2 Register

Offset
$08_{H}$

Reset Value
derivate-specific

| 15 | 14 | 8 |  |
| :---: | :---: | :---: | :---: |
| Res |  | ANG_RANGE |  |

W
7 4

| ANG_RANGE | ANG_DIR | PREDICT | AUTOCAL |  |
| :---: | :---: | :---: | :---: | :---: |
| w |  | w | w | w |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| ANG_RANGE | 14:4 | w | Angle Range ${ }^{1)}$ <br> Changes the representation of the angle output (AVAL and ASPD register) by multiplying the output with a factor ANG_RANGE/128. <br> $080_{\mathrm{H}}$ factor 1 (default), magnetic angle $-180^{\circ} . .180^{\circ}$ <br> mapped to values -16384.. 16383 <br> $200_{\mathrm{H}}$ factor 4 , magnetic angle $-45^{\circ} . .45^{\circ}$ mapped to values -16384 ..16383. Values outside this range are clamped to the limit value and S_OV flag is set. <br> $040_{\mathrm{H}}$ factor 0.5 , magnetic angle $-180^{\circ} . .180^{\circ}$ mapped to values -8192..8191) <br> Reset: $080_{H}$ |
| ANG_DIR | 3 | w | Angle Direction <br> Inverts angle and angle speed values and revolution counter behaviour. <br> Note: In case of changing ANG_DIR, AUTOCAL should be deactivated as explained under Note on Page 23. <br> $0_{B} \quad$ counterclockwise rotation of magnet <br> $1_{B} \quad$ clockwise rotation of magnet <br> Reset: $0_{B}$ |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| PREDICT | 2 | w | Prediction <br> Prediction of angle value based on current angle speed (see data sheet). <br> Note: In case of changing a PREDICT, AUTOCAL should be deactivated as explained under Note on Page 23. <br> $0_{B} \quad$ prediction disabled <br> $1_{B} \quad$ prediction enabled <br> Reset: derivate-specific |
| AUTOCAL | 1:0 | w | Autocalibration Mode <br> Automatic calibration of offset and amplitude synchronicity for applications with full-turn. Only 1 LSB corrected at each update. CRC check of calibration registers is automatically disabled if AUTOCAL activated. Autocalibration is described in the data sheet. Also see Chapter 4.1. <br> $00_{B}$ no auto-calibration <br> 01 ${ }_{B}$ auto-cal. mode 1: update every angle update cycle (FIR_MD setting) <br> $10_{\mathrm{B}}$ auto-cal. mode 2: update every 1.5 revolutions $11_{\mathrm{B}}$ auto-cal. mode 3: update every $11.25^{\circ}$ <br> Reset: derivate-specific |

1) Autocalibration and Revolution Counter work only for ANG_RANGE $=080_{\mathrm{H}}$. Activated autocalibration forces $360^{\circ}$ angle range regardless of ANG_RANGE setting.

## Interface Mode3 Register

MOD_3
Interface Mode3 Register

Offset
$09_{H}$

Reset Value
device-specific

15
8

w

| 7 | 4 | 2 | 1 | 0 |
| :---: | :---: | :---: | :---: | :---: |
| ANG_BASE |  | SPIKEF | SSC_OD | PAD_DRV |
| $w$ | $w$ | $w$ | $w$ |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| ANG_BASE | 15:4 | w | Angle Base <br> Sets the $0^{\circ}$ angle position ( 12 bit value). Angle base is factory-calibrated to make the $0^{\circ}$ direction parallel to the edge of the chip. $\begin{aligned} & 800_{\mathrm{H}}-180^{\circ} \\ & 000_{\mathrm{H}} 0^{\circ} \\ & 7 \mathrm{FF}_{\mathrm{H}}+179.912^{\circ} \end{aligned}$ <br> Reset: device-specific |
| SPIKEF | 3 | w | Analog Spike Filter of Input Pads <br> Filters voltage spikes on input pads (IFC, SCK and CSQ). <br> Additional delay of $10 \mu \mathrm{~s}$ for data input. <br> $0_{B} \quad$ spike filter disabled <br> $1_{B} \quad$ spike filter enabled <br> Reset: derivate-specific |
| SSC_OD | 2 | w | SSC-Interface Data Pin Output Mode <br> $0_{B} \quad$ Push-Pull <br> $1_{B}$ Open Drain <br> Reset: $0_{B}$ |
| PAD_DRV | 1:0 | w | Configuration of Pad-Driver <br> $00_{B}$ IFA/IFB/IFC: strong driver, DATA: strong driver, fast edge <br> $01_{B}$ IFA/IFB/IFC: strong driver, DATA: strong driver, slow edge <br> 10 ${ }_{B}$ IFA/IFB/IFC: weak driver, DATA: medium driver, fast edge <br> 11 ${ }_{B}$ IFA/IFB/IFC: weak driver, DATA: weak driver, slow edge <br> Reset: derivate-specific |

## Offset X Register



## Offset Y Register

| OFFY <br> Offset $\mathbf{Y}$ |
| :--- |
| Offset |
| $\mathbf{O B}_{\mathbf{H}}$ |

w

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| Y_OFFSET | $15: 4$ | w | Offset Correction of Y-value in digits <br> 12 -bit signed integer value of raw Y-signal offset <br> correction at $25^{\circ} \mathrm{C}$. <br> Reset: device-specific |

## Synchronicity Register

SYNCH
Synchronicity

Offset
$0 C_{H}$

Reset Value

## device-specific

15
8

w
4
3
0

| SYNCH | Res |
| :---: | :---: | :---: | :---: |

w

| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| SYNCH | 15:4 | w | Amplitude Synchronicity <br> 12-bit signed integer value of amplitude synchronicity correction (raw X amplitude divided by raw Y amplitude). For synchronicity correction, the offset compensated $Y$ value is multiplied by SYNCH. $\begin{aligned} & +2047_{D} \quad 112.494 \% \\ & 0_{D} \quad 100 \% \\ & -2048_{D} 87.500 \% \end{aligned}$ <br> Reset: device-specific |

## IFAB Register (multi-purpose)

| IFAB <br> IFAB Register |  | Offset$0 D_{H}$ |  |  | Reset Value device-specific |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 15 |  |  |  |  |  | 8 |
| ORTHO |  |  |  |  |  |  |
| w |  |  |  |  |  |  |
| 7 |  | 4 | 3 | 2 | 1 | 0 |
|  | ORTHO |  | FIR_UDR | IFAB_OD |  |  |
|  | w |  | w | w |  |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| ORTHO | 15:4 | w | Orthogonality Correction of $X$ and $Y$ Components 12-bit signed integer value of orthogonality correction. GMR element orthogonality correction. $\begin{aligned} & +2047_{D} 11.2445^{\circ} \\ & 0_{D} \quad 0^{\circ} \\ & -2048_{D}-11.2500^{\circ} \end{aligned}$ <br> Reset: device-specific |
| FIR_UDR | 3 | w | FIR Update Rate <br> Initial filter update rate (FIR) setting to be loaded into FIR_MD on startup. Changing of the FIR setting can only be done by writing to the FIR_MD bits via SPI after power-on. $\begin{array}{ll} 0_{B} & \text { FIR_MD }=‘ 10 ’(85.3 \mu \mathrm{~s}) \\ 1_{\mathrm{B}} & \text { FIR_MD }=\text { ' } 01 \text { ' }(42.7 \mu \mathrm{~s}) \end{array}$ <br> Reset: derivate-specific |
| IFAB_OD | 2 | w | IFA,IFB,IFC Output Mode $0_{B} \quad$ Push-Pull $1_{B} \quad$ Open Drain Reset: derivate-specific |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| IFAB_HYST (multi-purpose) | 1:0 | w | HSM and IIF Mode: Hysteresis <br> Switching hysteresis on direction change for HSM and IIF interface. $\begin{array}{ll} 00_{\mathrm{B}} & 0^{\circ} \\ 01_{\mathrm{B}} & 0.175^{\circ} \\ 10_{\mathrm{B}} & 0.35^{\circ} \\ 11_{\mathrm{B}} & 0.70^{\circ} \end{array}$ <br> SPC Mode: Unit Time <br> $00_{B} \quad 3.0 \mu \mathrm{~s}$ <br> $01_{\mathrm{B}} \quad 2.5 \mu \mathrm{~s}$ <br> $10_{\mathrm{B}} \quad 2.0 \mu \mathrm{~s}$ <br> $11_{\mathrm{B}} \quad 1.5 \mu \mathrm{~s}$ <br> Reset: derivate-specific |

## Interface Mode4 Register (multi-purpose)

```
MOD_4
Interface Mode4 Register
```

Offset
$0 E_{H}$
device-specific

15
$9 \quad 8$

| 1 | TCO_X_T | HSM_PL <br> $\mathbf{P}$ |
| :---: | :---: | :---: | :---: |




| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| TCO_X_T | $15: 9$ | w | Offset Temperature Coefficient for X-Component <br> 7-bit signed integer value of X-offset temperature <br> coefficient. This register is used both with autocalibration <br> and without autocalibration. If autocalibration is <br> deactivated, overwrite only with the default value. If <br> autocalibration is activated, do not write this bitfield. See <br> "Offset temperature compensation" on Page 97. <br> Reset: device-specific |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| HSM_PLP (multi-purpose) | 8:5 | w | Hall Switch Mode: Pole-Pair Configuration <br> $0000_{\text {B }} 1$ pole pairs <br> $0001_{\text {B }} 2$ pole pairs <br> $0010_{B} 3$ pole pairs $\cdots \text { … }$ <br> $1101_{\text {B }} 14$ pole pairs <br> $1110_{B} 15$ pole pairs <br> $1111_{\text {B }} 16$ pole pairs <br> Pulse-Width-Modulation Mode: Error Indication $x x 0 x_{B}$ error indication enabled $x x 1 x_{B}$ error indication disabled <br> Incremental Interface Mode: Absolute Count Interface counts to absolute value at startup $x 0 x_{B}$ absolute count enabled $\mathrm{x} 1 \mathrm{xx}_{\mathrm{B}}$ absolute count disabled <br> SPC Mode: Total Trigger Time <br> Duration of the master pulse to trigger SPC output $0000_{\mathrm{B}} 90 *$ UT $0100_{\mathrm{B}} \mathrm{t}_{\text {mlow }}+12$ UT <br> Reset: derivate-specific |
| IFAB_RES (multi-purpose) | 4:3 | w | Pulse-Width-Modulation Mode: Frequency <br> Selection of PWM frequency. $\begin{array}{\|ll} 00_{\mathrm{B}} & 244 \mathrm{~Hz} \\ 01_{\mathrm{B}} & 488 \mathrm{~Hz} \\ 10_{\mathrm{B}} & 977 \mathrm{~Hz} \\ 11_{\mathrm{B}} & 1953 \mathrm{~Hz} \end{array}$ <br> Incremental Interface Mode: IIF resolution <br> $00_{B} \quad 12 b i t, 0.088^{\circ}$ step <br> $01_{B} \quad 11$ bit, $0.176^{\circ}$ step <br> $10_{B} \quad 10 b i t, 0.352^{\circ}$ step <br> $11_{\mathrm{B}} \quad 9$ bit, $0.703^{\circ}$ step <br> SPC Mode: SPC Frame Configuration <br> $00_{B} \quad$ 12bit angle <br> $01_{B} \quad$ 16bit angle <br> $10_{B} \quad 12$ bit angle +8 bit temperature <br> $11_{B} \quad 16$ bit angle +8 bit temperature <br> Reset: derivate-specific |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| IF_MD | 1:0 | w | Interface Mode on IFA,IFB,IFC <br> Any derivate can be configurated to operate in any of the four following protocols on the IFA, IFB and IFC outputs. Reconfiguration is required at every start-up, else the default protocol of the derivate will be used. <br> SSC interface is always active in parallel on pins SCK, CSQ and DATA. <br> $00_{B}$ IIF <br> 01 ${ }^{\text {B }}$ PWM <br> 10 $\mathrm{B}_{\mathrm{B}}$ HSM <br> $11_{\mathrm{B}} \quad \mathrm{SPC}^{1)}$ <br> Reset: derivate-specific |



Figure 6-12 Timing of angle calculation in SPC. Trigger Nibble low time corresponds to slave number.


## Temperature Coefficient Register

| TCO_Y <br> Temperature Coefficient Register | Offset <br> $\mathbf{O F}_{\mathbf{H}}$ | Reset Value <br> device-specific |
| :--- | :--- | :--- |
| 15 |  |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| TCO_Y_T | 15:9 | w | Offset Temperature Coefficient for Y-Component 7-bit signed integer value of Y-offset temperature coefficient. This register is used both with autocalibration and without autocalibration. If autocalibration is deactivated, overwrite only with the default value. If autocalibration is activated, do not write this bitfield. See "Offset temperature compensation" on Page 97. Reset: device-specific |
| SBIST | 8 | w | Startup-BIST  <br> $0_{B}$ Startup-BIST disabled <br> $1_{B}$ Startup-BIST enabled <br> Reset: $1_{B}$  |
| CRC_PAR | 7:0 | w | CRC of Parameters <br> CRC of parameters from address $08_{H}$ to $0 F_{H}$. If any settings within these registers are changed, this CRC has to be changed accordingly. <br> Reset: device-specific |

## Offset temperature compensation

The TLE5012B compensates the temperature dependence of the X - and Y -offsets during run-time by using an integrated temperature measurement (see register TEMPER on Page 84) and applying factory-calibrated temperature coefficients for the offsets. At a chip temperature of $T$, the resulting offset correction parameters are given by:

Offset_X/Y[T] = Offset_X/Y[25$\left.{ }^{\circ} \mathrm{C}\right]+\left(T C O \_X / Y \_T *\left(T E M P E R[T]-T E M P E R\left[25^{\circ} \mathrm{C}\right]\right)\right) / 128$

Temperature compensation of the offsets is only active, if autocalibration is disabled. If auto-calibration is enabled, TCO_ $X_{-} T$ and TCO_Y_T are automatically set to 0 . Once auto-calibration is deactivated, laser-fused calibration values are loaded into TCO_X_T and TCO_Y_T.

## X-raw Value Register

ADC_X

## Offset

Reset Value
X-raw value
$10_{H}$
$\mathbf{0 0 0 0}_{\mathrm{H}}$
$\square$
ADC_X
$r$

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| ADC_X | $15: 0$ | r | ADC value of X-GMR <br> 16-bit signed integer raw X value. Read-out of this <br> register will update ADC_Y <br> Reset: $0_{H}$ |

## Y-raw Value Register

ADC_Y
Y-raw value
Offset
Reset Value
$11_{H}$ $\mathbf{0 0 0 0}_{\mathrm{H}}$

r

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| ADC_Y | $15: 0$ | r | ADC value of Y-GMR <br> $16-$ bit signed integer raw Y value. Updated when ADC_X <br> or ADC_Y is read. <br> Reset: $0_{H}$ |

TLE5012B

D_MAG Register


| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| MAG | $9: 0$ | ru | Angle Vector Magnitude <br> Unsigned Angle Vector Magnitude after X, Y error <br> compensation (due to temperature). <br> This field allows additional safety checks. <br> Formula: <br> MAG $=\left(\right.$ SQRT $\left.\left(X^{*} X+Y^{*} Y\right)\right) / 64$ <br> Reset: $0_{H}$ |

## T_RAW Register


ru

| Field | Bits | Type | Description |
| :--- | :--- | :--- | :--- |
| T_TGL | 15 | ru | Temperature Sensor Raw-Value Toggle <br> Toggles after every new temperature value (T_RAW). <br> Reset: $0_{B}$ |
| T_RAW | $9: 0$ | ru | Temperature Sensor Raw-Value <br> Temperature at ADC. This value is not compensated with <br> the offset temperature. T_RAW range is not limited as <br> TEMPER. T_RAW is an unsigned value. <br> T[ $\left.{ }^{\circ} \mathrm{C}\right]=\left(\mathrm{T}\right.$ RAW[dig]-369[dig]-T25O[dig]) $/ 2.776\left[d i g /{ }^{\circ} \mathrm{C}\right]$ <br> Reset: $0_{H}$ |

## Increment Counter Register

| IIF_CNT |  | Offset |  |  | Reset Value |
| :---: | :---: | :---: | :---: | :---: | :---: |
| IIF Counter value |  | $2 \mathbf{2 0}_{\text {H }}$ |  |  | $\mathbf{0 0 0 0}_{\mathrm{H}}$ |
| 15 | 13 |  |  |  | 0 |
| Res | IIF_CNT |  |  |  |  |
| ru |  |  |  |  |  |
| Field |  | Bits | Type | Description |  |
| IIF_CNT |  | 13:0 | ru | Coun Interna which It can senso There registe 2 to 5 synch Reset | interface, ull turn. s between er side. IFAB_RES tal interface), CNT for the |

Temperature $25^{\circ} \mathrm{C}$ offset value

| T250 <br> Tempera |  | Offset$3^{3}{ }_{H}$ |  |  |  | Reset Value device-specific |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 15 | 14 | 13 | 12 | 11 | 10 | 9 |  | 8 |
|  |  |  | T25 |  |  |  |  | es |
| $r$ |  |  | r |  |  |  |  |  |
| 7 | 6 | 5 | 4 | 3 | 2 | 1 |  | 0 |
|  |  |  |  |  |  |  |  |  |


| Field | Bits | Type | Description |
| :---: | :---: | :---: | :---: |
| T250 | 15:9 | r | Temperature $25^{\circ} \mathrm{C}$ Offset value <br> Signed offset value at $25^{\circ} \mathrm{C}$ temperature; $1 \mathrm{dig}=0.36^{\circ} \mathrm{C}$. <br> T25O = T_RAW(@25 ${ }^{\circ}$ C)[dig]-439[dig]. <br> Reset: device-specific |
| User's Manual |  |  | 101 Rev. 1.2, 2018-02 |

## $7 \quad$ Pre-Configured Derivates

Derivates of the TLE5012B are available with different pre-configured register settings for specific applications. The default configuration of all derivates is described below (see Chapter 7.6 for the respective fuse configuration) and can be changed at start-up via SSC interface.

### 7.1 IIF-type: E1000

The TLE5012B E1000 is preconfigured for Incremental Interface and fast angle update rate ( $42.7 \mu \mathrm{~s}$ ). It is most suitable for BLDC motor commutation.

- Incremental Interface A/B mode.
- 12 bit mode, one count per $0.088^{\circ}$ angle step.
- Absolute count enabled.
- Autocalibration mode 1 enabled.
- Prediction disabled.
- Hysteresis set to $0.703^{\circ}$.
- IFA/IFB/IFC pins set to push-pull output.
- SSC interface's DATA pin set to push-pull output.
- IFA/IFB/IFC pins set to strong driver, DATA pin set to strong driver, fast edge.
- Voltage spike filter on input pads disabled.


### 7.2 HSM-type: E3005

The TLE5012B E3005 is preconfigured for Hall-Switch-Mode and fast angle update rate ( $42.7 \mu \mathrm{~s}$ ). It is most suitable as a replacement for three Hall switches for BLDC motor commutation.

- Number of pole pairs is set to 5 .
- Autocalibration mode 1 enabled.
- Prediction enabled.
- Hysteresis set to $0.703^{\circ}$.
- IFA (HS1)/IFB (HS2)/IFC (HS3) pins set to push-pull output.
- SSC interface's DATA pin set to push-pull output.
- IFA/IFB/IFC pins set to strong driver, DATA pin set to strong driver, fast edge.
- Voltage spike filter on input pads disabled.


### 7.3 PWM-type: E5000

The TLE5012B E5000 is preconfigured for Pulse-Width-Modulation interface. It is most suitable for steering angle and actuator position sensing.

- PWM frequency is 244 Hz .
- Filter update time is $85.4 \mu \mathrm{~s}$.
- Error indication enabled.
- Autocalibration disabled
- Prediction disabled
- Hysteresis disabled.
- IFA (PWM) pin set to push-pull output.
- SSC interface's DATA pin set to push-pull output.
- IFA/IFB/IFC pins set to weak driver, DATA pin set to medium driver, fast edge.
- Voltage spike filter on input pads enabled.


### 7.4 PWM-type: E5020

The TLE5012B E5020 is preconfigured for Pulse-Width-Modulation interface with high frequency. It is most suitable for steering angle and actuator position sensing.

- PWM frequency is 1953 Hz .
- Filter update time is $42.7 \mu \mathrm{~s}$.
- Error indication enabled
- Autocalibration mode 2 enabled.
- Prediction disabled
- Hysteresis disabled.
- IFA (PWM) pin set to open-drain output.
- SSC interface's DATA pin is set to push-pull output.
- IFA/IFB/IFC pins set to weak driver, DATA pin set to medium driver, fast edge.
- Voltage spike filter on input pads enabled.


### 7.5 SPC-type: E9000

The TLE5012B E9000 is preconfigured for Short-PWM-Code interface. It is most suitable for steering angle and actuator position sensing.

- SPC unit time is $3 \mu \mathrm{~s}$.
- Duration of the master pulse to trigger SPC output is $90 * \mathrm{UT}$.
- 12-bit angle resolution.
- Filter update time is $85.4 \mu \mathrm{~s}$.
- Autocalibration disabled
- Prediction disabled
- Hysteresis disabled.
- IFA (SPC) pin set to open-drain output.
- SSC interface's DATA pin set to push-pull output.
- IFA/IFB/IFC pins set to weak driver, DATA pin set to medium driver, fast edge.
- Voltage spike filter on input pads enabled.

TLE5012B

## $7.6 \quad$ Fuse Values

The derivate specific reset values for the configuration registers, which are stored in laser fuses on the sensor, are shown in Figure 7-1.

|  | Interface Mode2 Register |  |  |  |  |  |  |  |  |  |  |  |  | Interface Mode3 Register |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |  |
|  | ANG_RANGE |  |  |  |  |  |  |  |  |  |  | ANG_DIR | PREDICT | AUTOCAL |  | SPIKEF | SSC_OD | PAD_DRV |  |
| TLE5012B E1000 (IIF) | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 |
| TLE5012B E3005 (HSM) | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 1 | 0 | 0 | 0 | 0 |
| TLE5012B E5000 (PWM) | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 1 | 0 |
| TLE5012B E5020 (PWM) | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 1 | 0 | 1 | 0 |
| TLE5012B E9000 (SPC) | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 0 | 1 | 0 |


|  |  | IFAB Register |  |  |  | Interface Mode4 Register |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $\text { FIR_UDR } \mid \text { FAB_OD\|FAB_HYST }$ |  |  |  |  |  |  |  |  |  |  |  |
|  | SBIST |  |  |  |  | HSM_PLP |  |  |  | IFAB_RES |  | IF_MD |  |
| TLE5012B E1000 (IIF) | 1 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 1 | 0 | 0 | 0 | 0 |
| TLE5012B E3005 (HSM) | 1 | 1 | 0 | 1 | 1 | 0 | 1 | 0 | 0 | 0 | 0 | 1 | 0 |
| TLE5012B E5000 (PWM) | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 |
| TLE5012B E5020 (PWM) | 1 | 1 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 1 | 0 | 1 |
| TLE5012B E9000 (SPC) | 1 | 0 | 1 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 0 | 1 | 1 |

Interface Mode1 Register

|  | Interface Mode1 Register |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | FIR_MD |  | CLK_SEL | DSPU_HOLD | IIF_MOD |  |
| TLE5012B E1000 (IIF) | 0 | 1 | 0 | 0 | 0 | 1 |
| TLE5012B E3005 (HSM) | 0 | 1 | 0 | 0 | 0 | 0 |
| TLE5012B E5000 (PWM) | 1 | 0 | 0 | 0 | 0 | 0 |
| TLE5012B E5020 (PWM) | 0 | 1 | 0 | 0 | 0 | 0 |
| TLE5012B E9000 (SPC) | 1 | 0 | 0 | 0 | 0 | 0 |

Figure 7-1 Derivate-specific fuse settings
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[^0]:    1) External clock feature is not available in IIF or HSM interface mode
[^1]:    1) Not subject to production test - verified by design/characterization
[^2]:    1) existing error may remain in STAT register even after SSC read-out due to asynchronity between SSC write of AC_STAT register and internal firmware execution. Thus this activation bit should only be cleared during start-up.
